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**Advanced Device Concepts**  
**and Research:**  
**Self-Assembled Nanostructures**

Presented by  
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Quantum Science Research  
Hewlett-Packard Laboratories

[www.hpl.hp.com/research/qsr](http://www.hpl.hp.com/research/qsr)

MSE Colloquium  
Stanford University  
November 15, 2002



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# Outline

**Limits of Device Scaling**

**Alternative Device Concepts**

**Self-Assembled Nanostructures**

Forming small structures

Putting them where we want them

Zero- and one-dimensional structures

Catalyzed nanowire growth

Strain from lattice mismatch

Nanowire transistor (speculation)

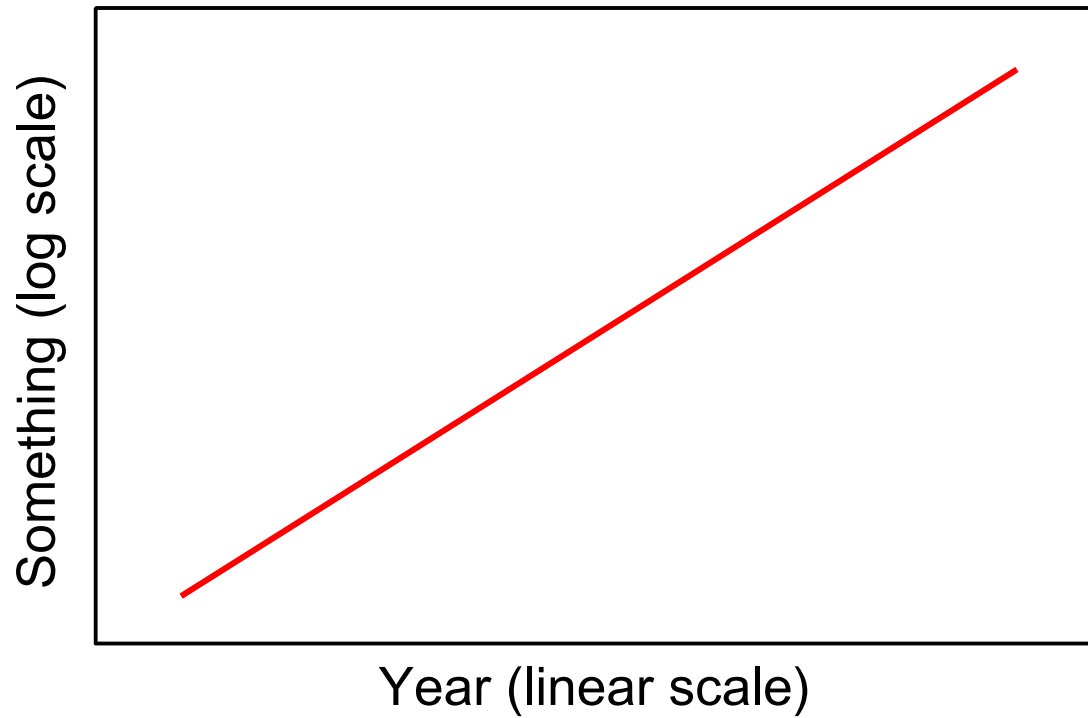
**Enabling Concept**

Defect Tolerance



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## Moore's Law (General Case)

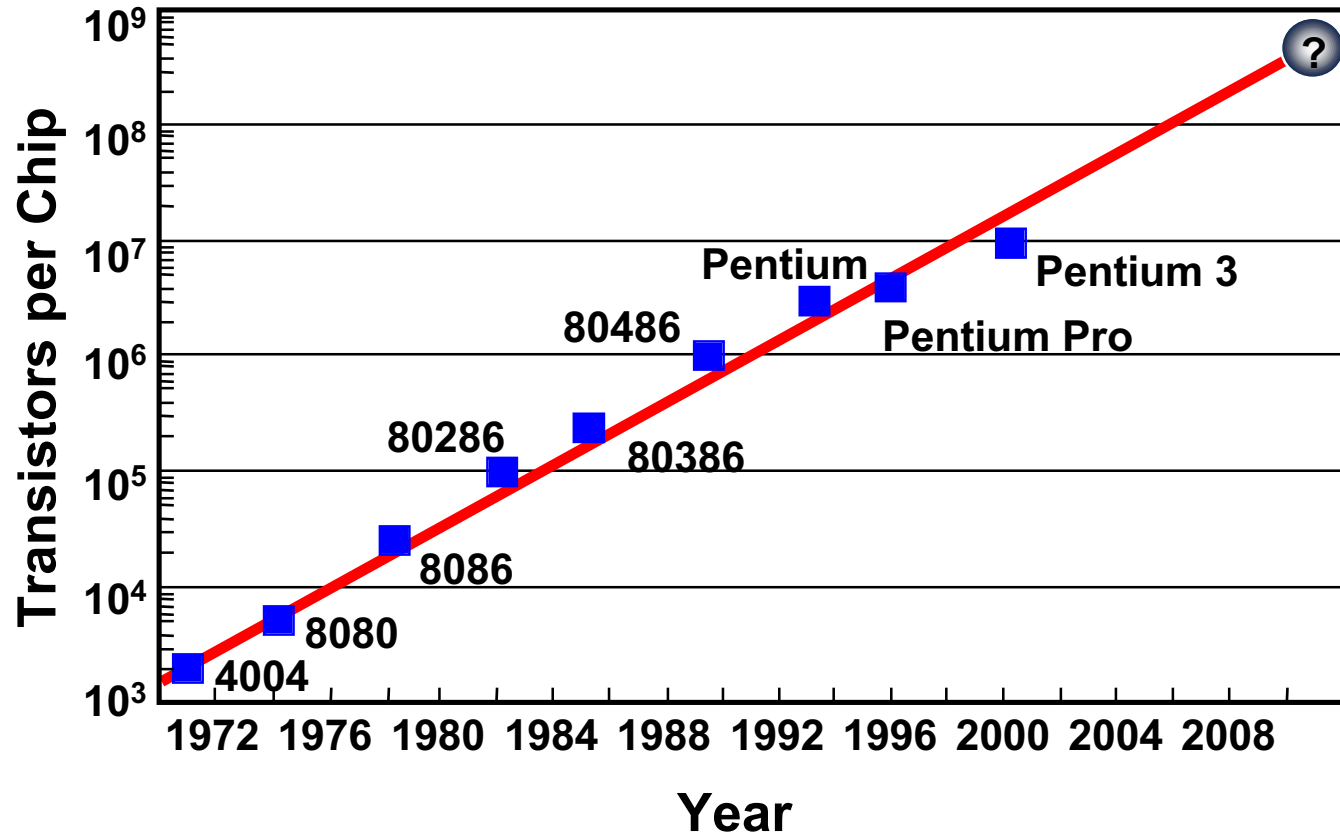


**Even Dilbert uses Moore's Law**

(Reference: Scott Adams "Dilbert," July 15, 1997)

# Moore's Law

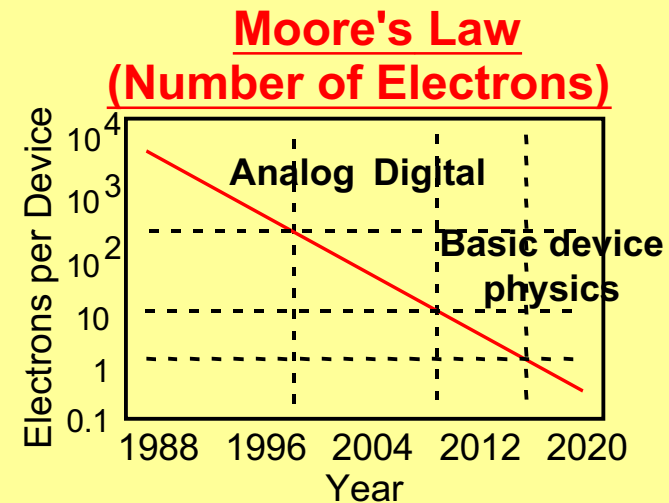
## Number of Transistors



# Critical Issues

## Device size and density

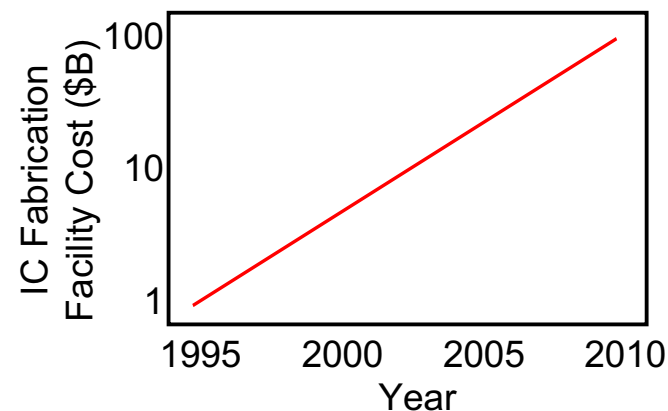
- Physically small features
- Operation with small features
- Limited number of electrons
- Interconnections



## Cost

- Minimize expensive lithography
- Self (or directed) assembly
- Simpler architecture
- Defect-tolerant architecture

## Moore's "Second Law" Cost of IC Fabrication Facility



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## Potential Devices

Single-electron devices  
Quantum cellular automata  
Molecular electronics  
Quantum computing



# Single-Electron Device

Minimum number of electrons

Coulomb blockade

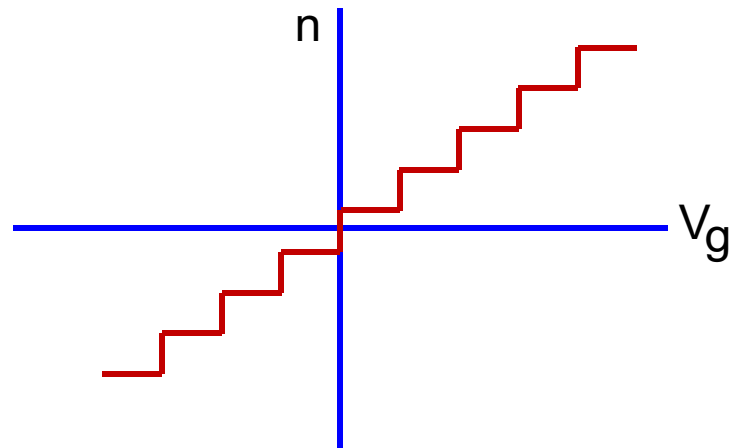
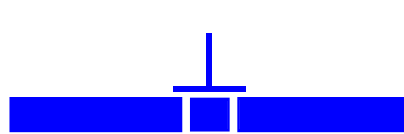
Energy to add single electron

$$E = q^2/2C$$

1 aF  $\sim$  80 meV  $\sim$  3 kT at 300 K

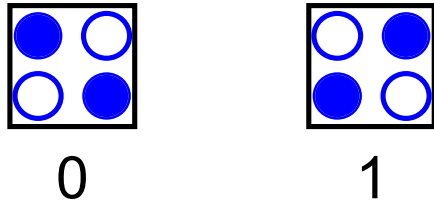
Can control charging by gate electrode

Sensitive to fractional background charge

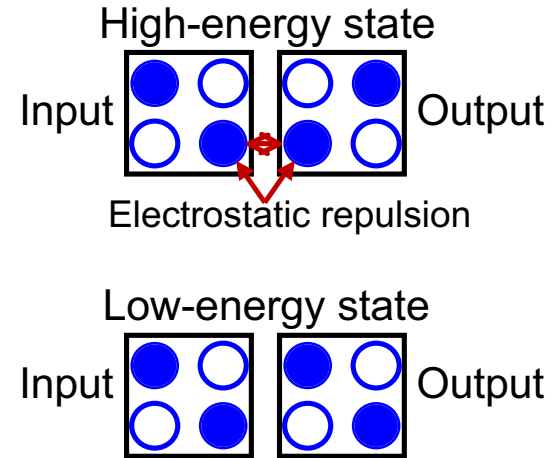


# Quantum Cellular Automata

## Cell with two possible polarizations

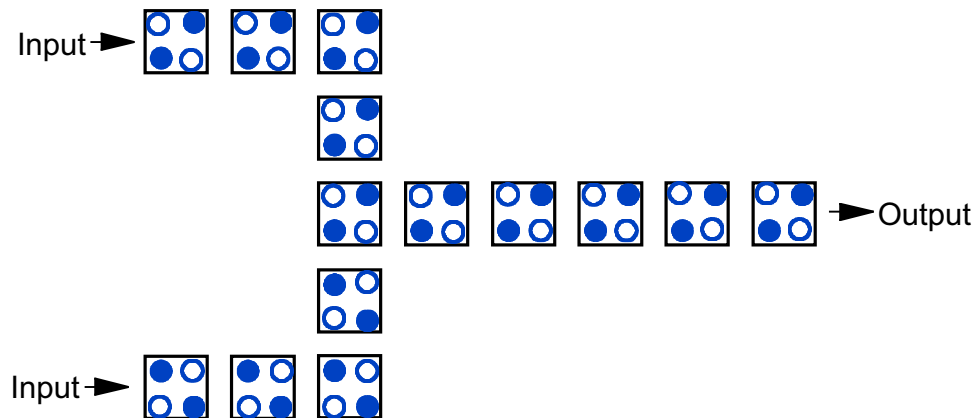


## Two interacting cells



Electrostatic interaction between adjacent cells  
Don't need wires to individual cells  
Add energy to prevent "sticking"  
Clocking...perhaps through substrate or overlayer

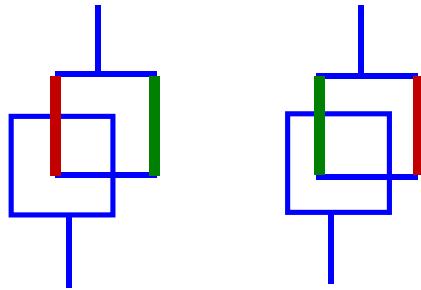
## Logic



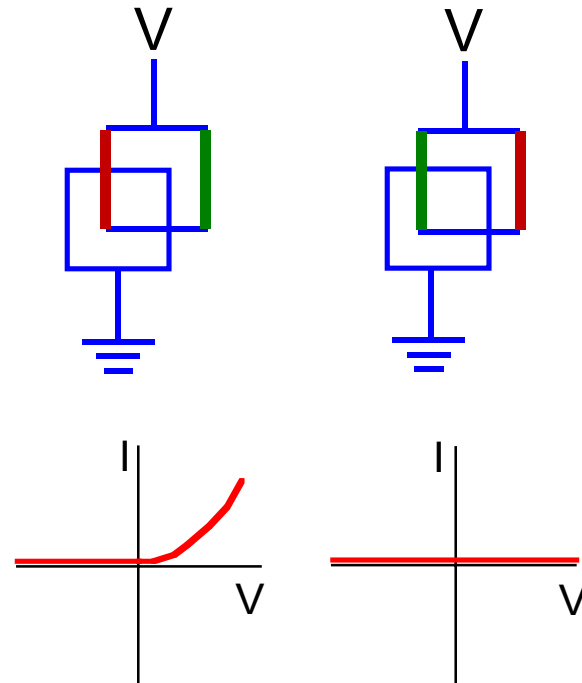


# Molecular Electronics

Organic molecule with two states  
of different electronic conductivity



Switch small group of molecules on nanowires  
Eventually switch single molecule  
Switching time?



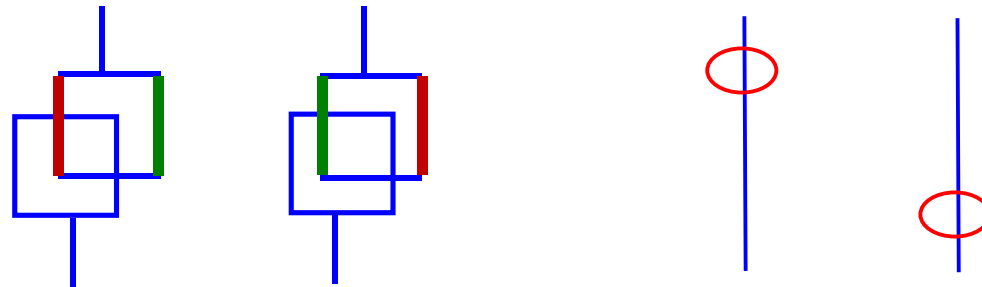
C. P. Collier, *et al*, Science **289**,  
1172 (18 August 2000)

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# Molecular Electronics: Switching

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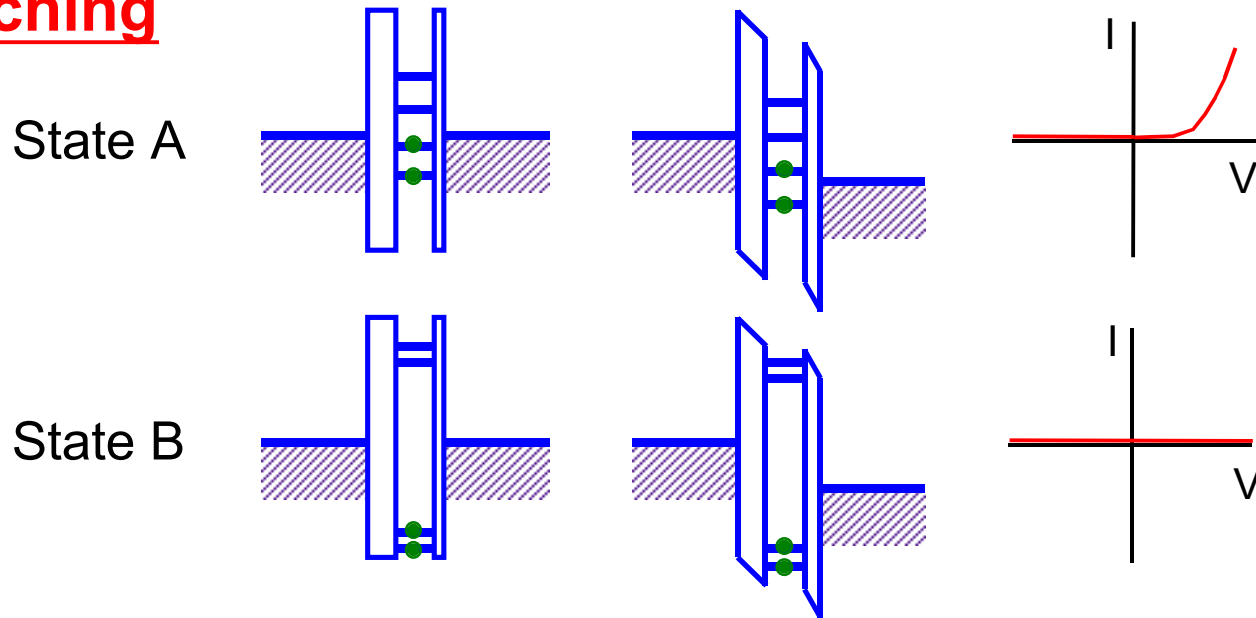
Electronic reconfiguration of molecular structure  
Charging of internal node within molecule  
Possibly modify bonding of molecule to electrode



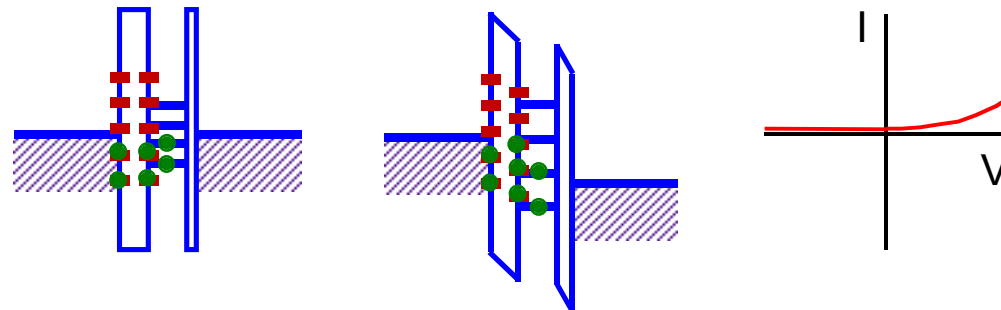
C P Collier, E W Wong, M Belohradsky,  
F M Raymo, J F Stoddart, P J Kuekes,  
R S Williams, and J R Heath, Science,  
vol. 285, p. 391, 16 July 1999

# Molecular Electronics

## Switching



## Interfaces: Charge Trapping



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## Potential Devices

Single-electron devices  
Quantum cellular automata  
Molecular electronics  
Quantum computing  
(Exciting, but speculative)

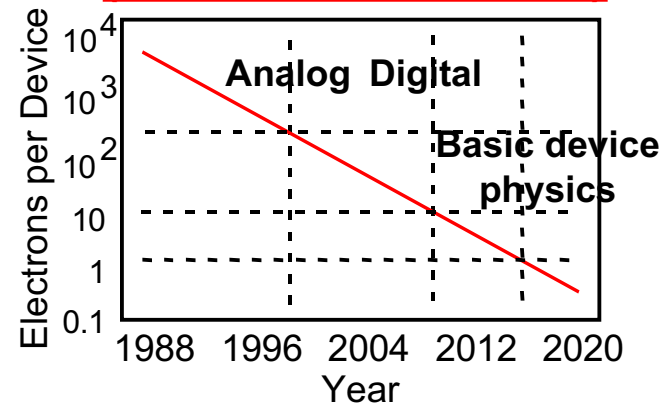


# Critical Issues

## Device size and density

- Physically small features
- Operation with small features
- Limited number of electrons
- Interconnections

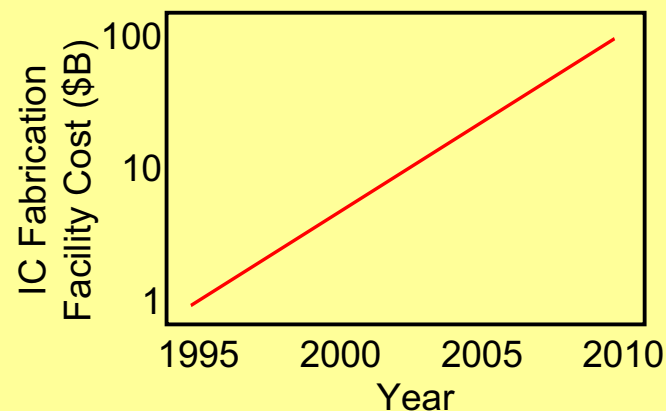
## Moore's Law (Number of Electrons)



## Cost

- Minimize expensive lithography
- Self (or directed) assembly
- Simpler architecture
- Defect-tolerant architecture

## Moore's "Second Law" Cost of IC Fabrication Facility



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# Advanced Lithography

## Near-term

Deep UV: I-line: 365 nm

Excimer: 248, 193 nm

Phase-shift masks

Contrast enhancement

## Future

Electron beam: Serial

Scanned probe: Serial

x-ray: Parallel (masks?)

Extreme ultraviolet 13 nm

Parallel

Reflective optics

Nanoimprinting



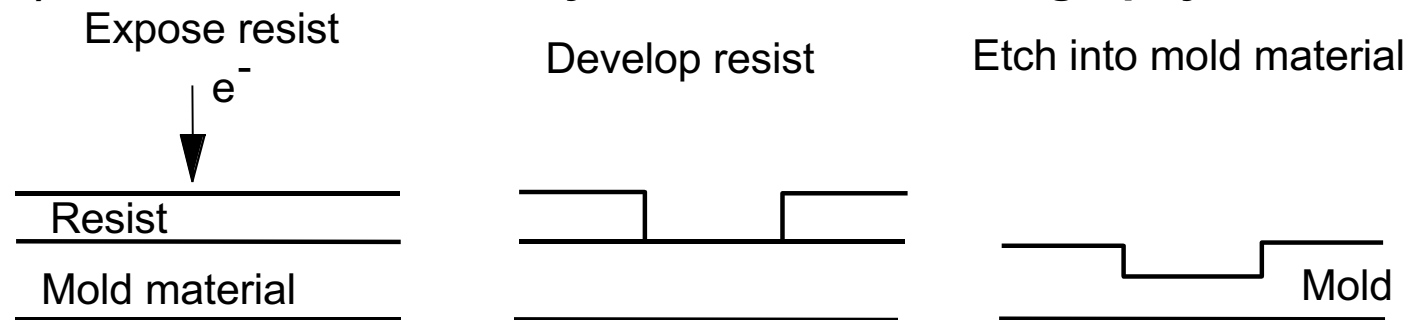
# Nanoimprinting Technology

Fine features (10's nm)

Lower cost

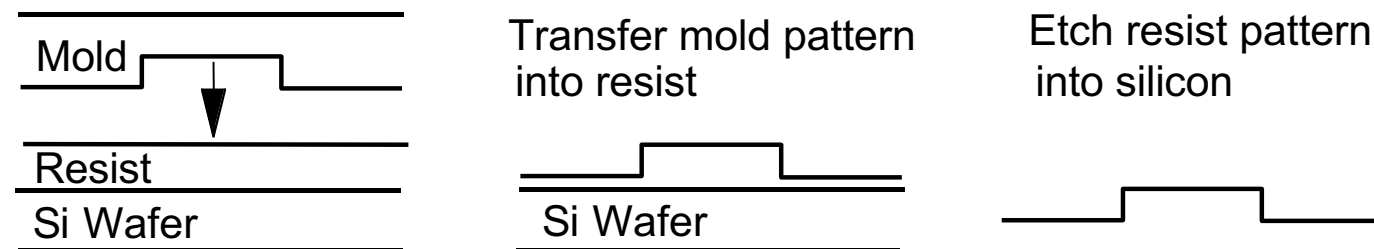
Define many elements simultaneously

## 1) Make reusable mold by electron-beam lithography



## 2) Form nanoscale feature in substrate (Si)

All features formed in parallel



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# Self-Assembled Nanostructures 0D Islands and 1D Nanowires on Si

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## **Conventional scaling will reach its limits**

Use directed-assembly to extend Moore's law

Determine critical dimensions by choice of materials and deposition kinetics ("self assembly"), not lithography

Use lithography to position devices or arrays of devices ("directed assembly")

## **Use small-size effects to perform logic, storage, and computation**

Coulomb blockade

Quantum confinement





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## Self (or Directed) Assembly

### **Methods of self- or directed- assembly**

Strain from lattice mismatch

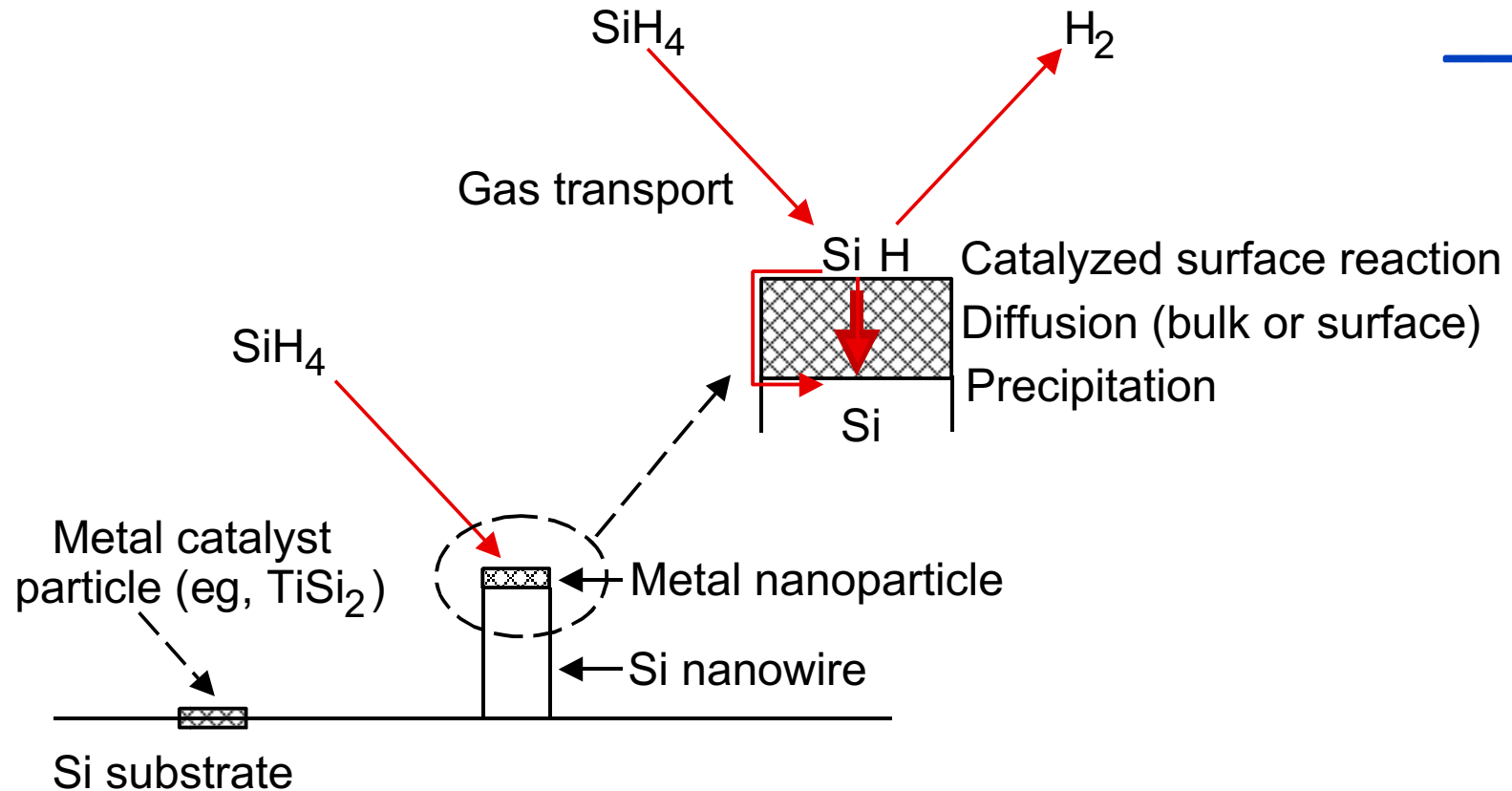
Catalytic wire growth on nanoparticle

### **Thermodynamically assembled structures**

Several percent defects

Need defect-tolerant architecture

# Metal Catalyzed Nanowire Growth



## Integration of Nanowires with CMOS

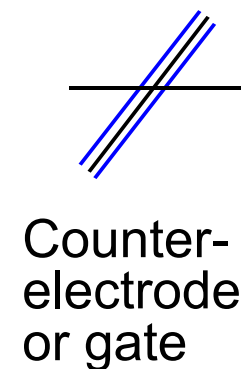
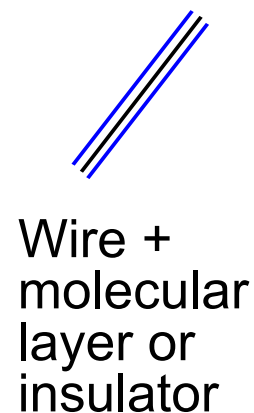
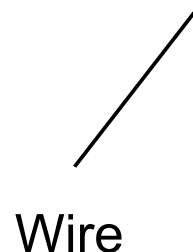
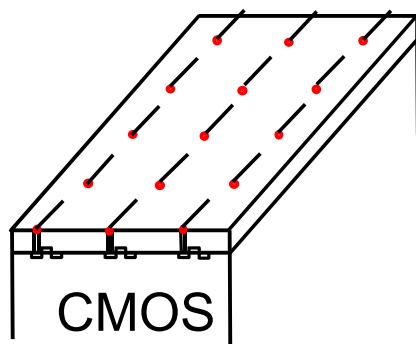
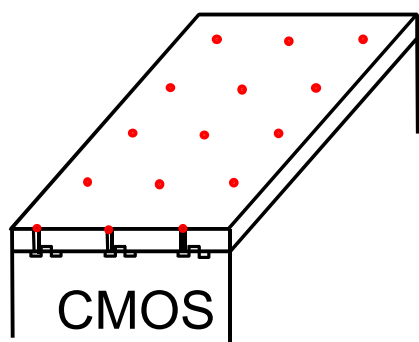
CMOS provides gain and interface circuitry

Partially processed CMOS (700°C)

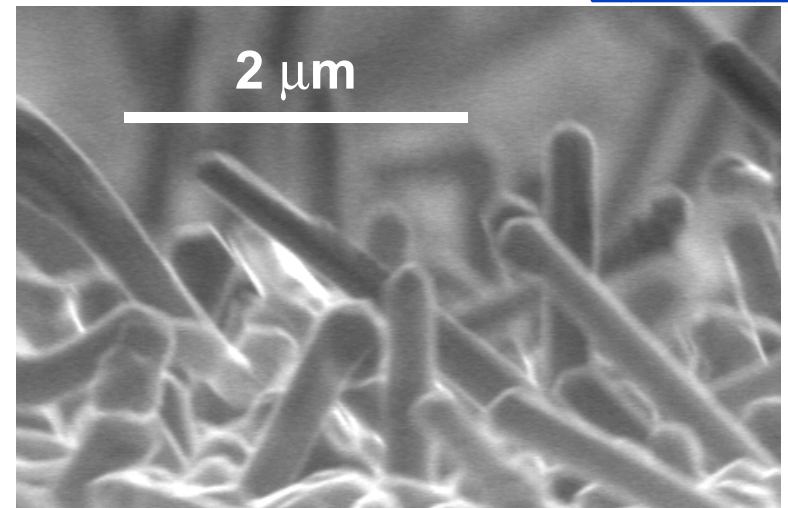
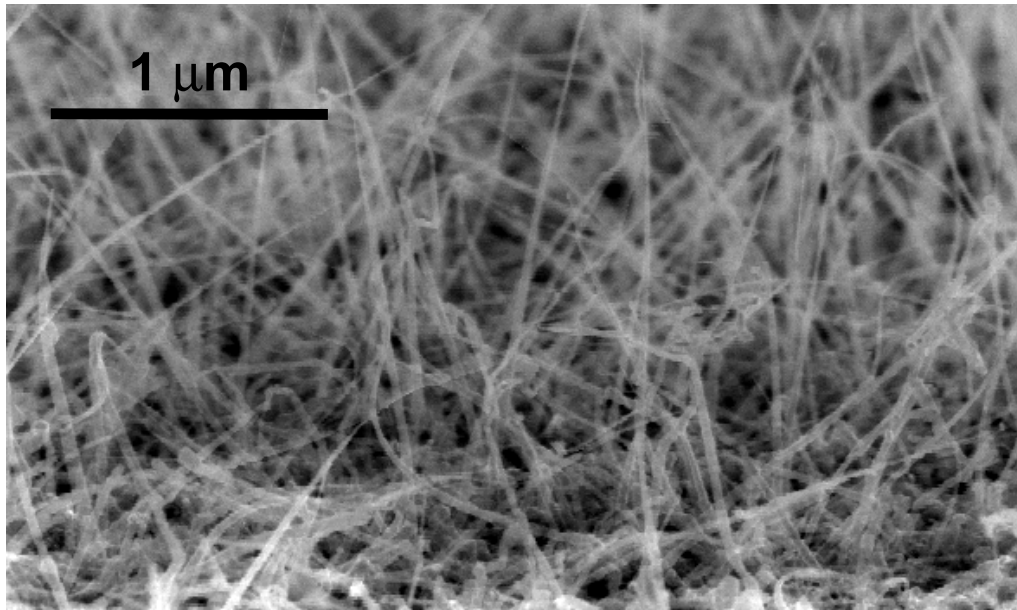
Fully processed CMOS (400°C)

Perhaps as interconnections for molecular electronics

Perhaps place some modulating element within wire

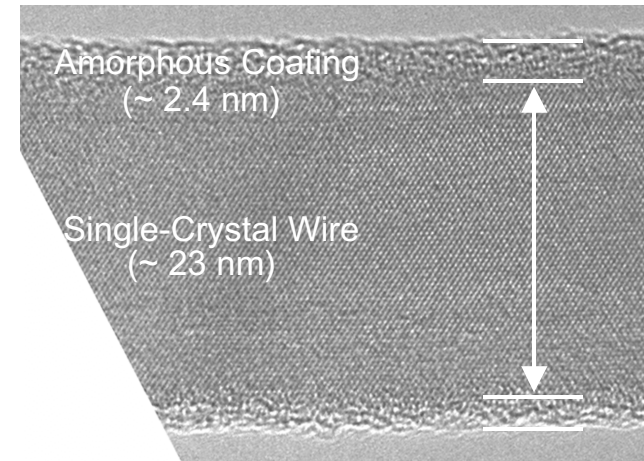
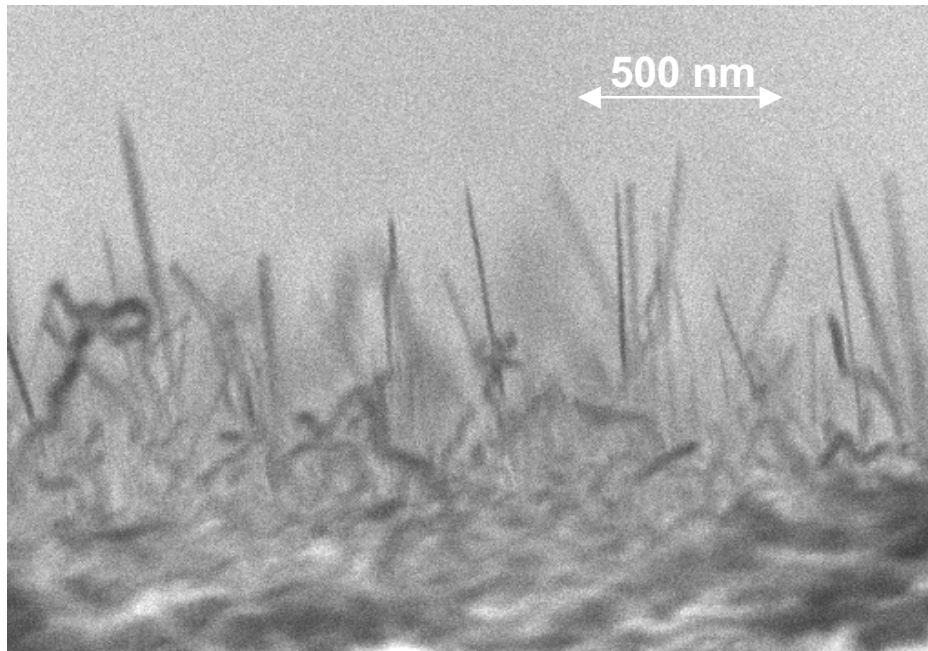


# Metal-Catalyzed Si Nanowire Growth



With Xuema Li and Tan Ha, Hewlett-Packard Labs

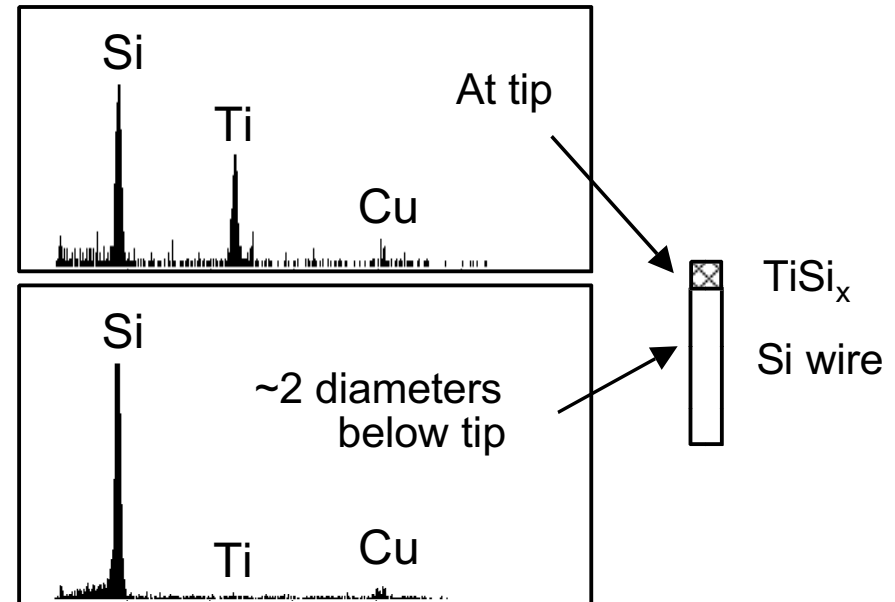
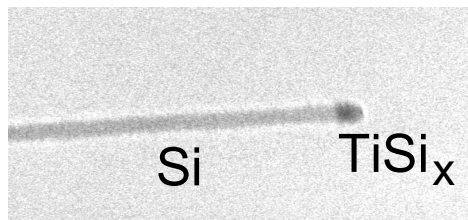
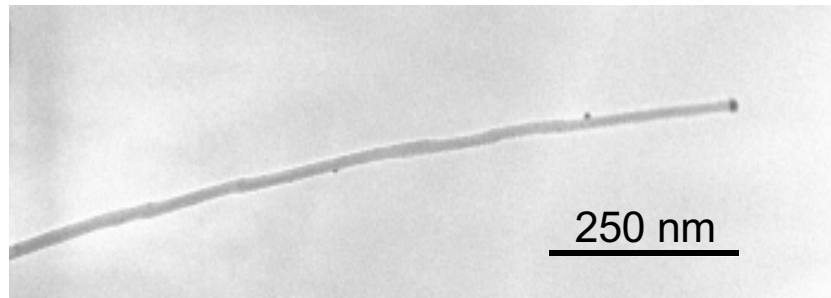
# Dense Si Nanowires from $\text{TiSi}_x$ Islands



Micrographs by Thorsten Hesjedal,  
Stanford University

# Ti-Nucleated Si Nanowire

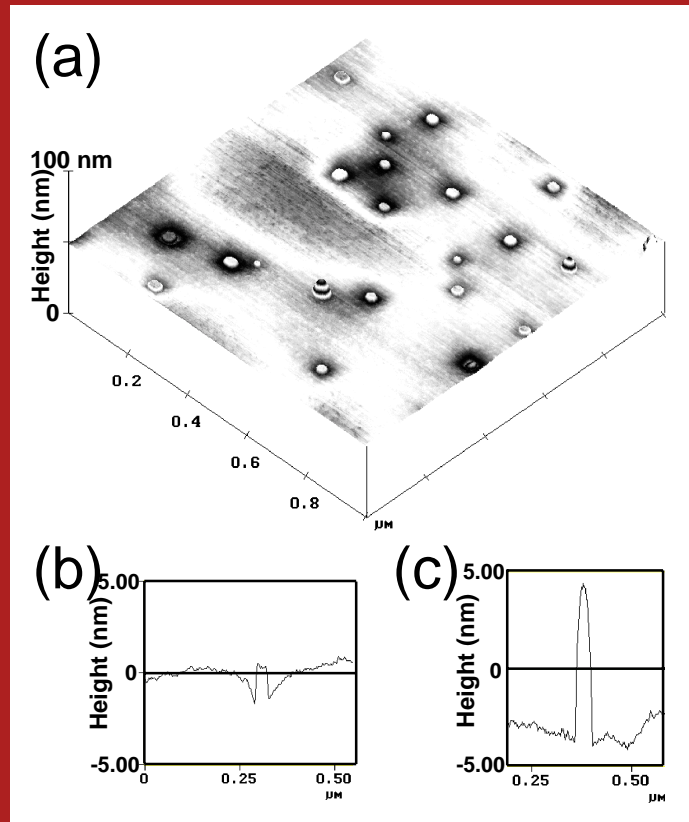
## Energy-Dispersive X-Ray Spectroscopy



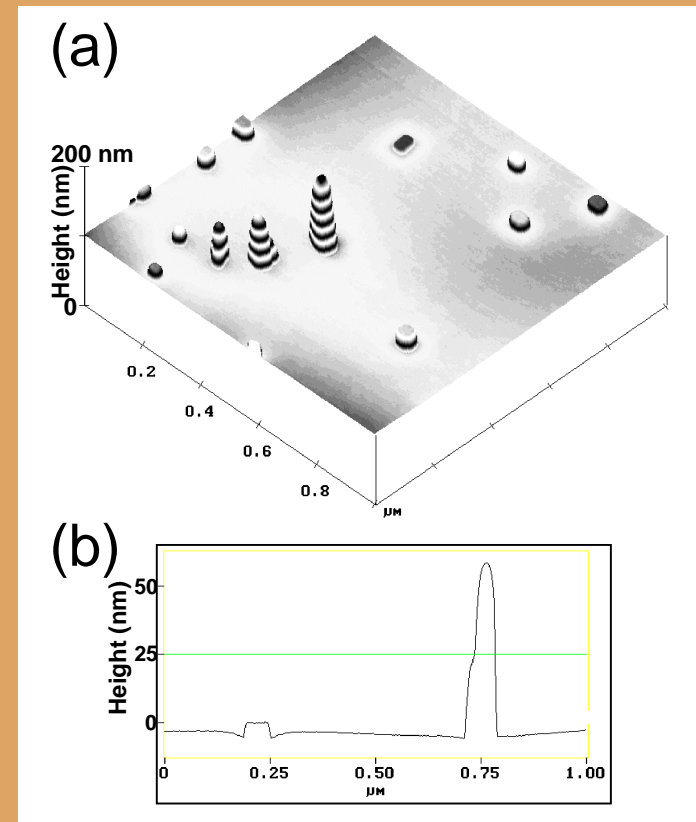
Analysis by  
Thorsten Hesjedal (Stanford University)  
David Basile (Agilent Laboratories)

# Surface Reaction Rate Limited Region of Growth

## Initial Stage of Wire Growth



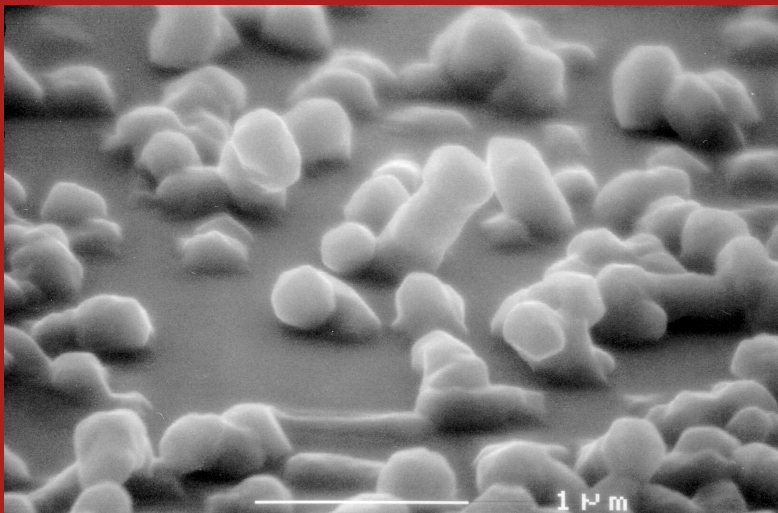
## Subsequent Stage of Wire Growth



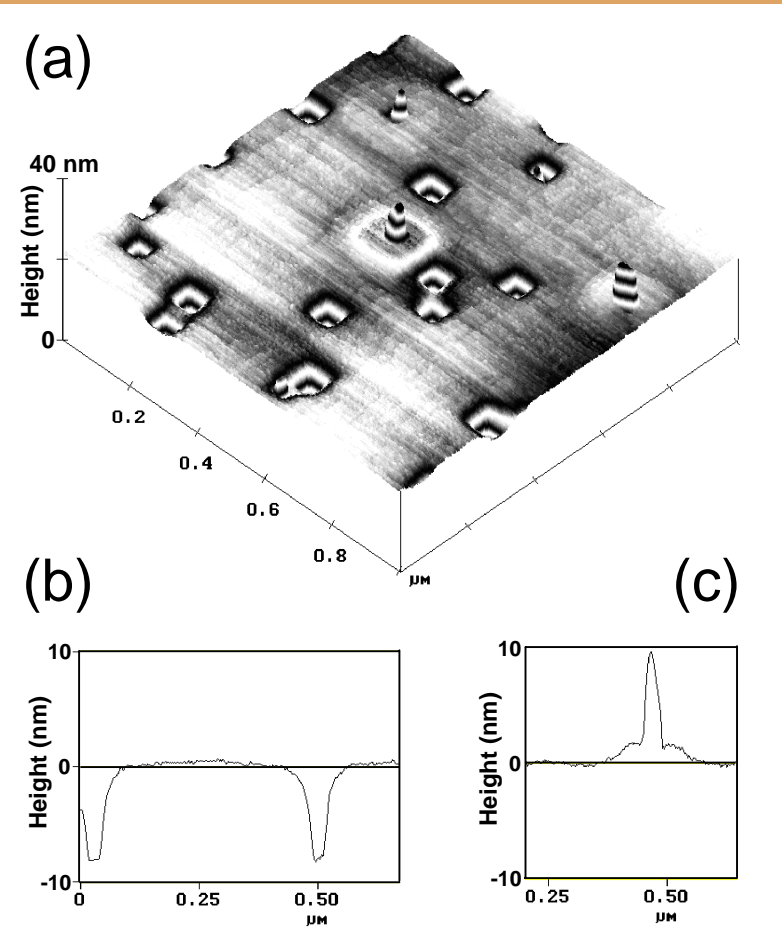
## Higher temperature

Uncatalyzed growth rate significant

Surface Reaction Rate Limited Region  
 $\text{SiH}_2\text{Cl}_2$  at  $920^\circ\text{C}$



Mass Transport Limited Region  
 $\text{SiH}_4$  at  $920^\circ\text{C}$





## Catalytic Nuclei: Material

### Desired characteristics:

Not a deep energy level in Si bandgap

Low solid solubility in Si

Liquid eutectic below deposition temperature  
(for VLS growth)

**Au:** Liquid eutectic:  $\sim 360^\circ\text{C}$  for Si and Ge

$E_t - E_i \sim 0$ : Mid-gap g-r center

$N_{ss} = 10^{17} \text{ cm}^{-3}$

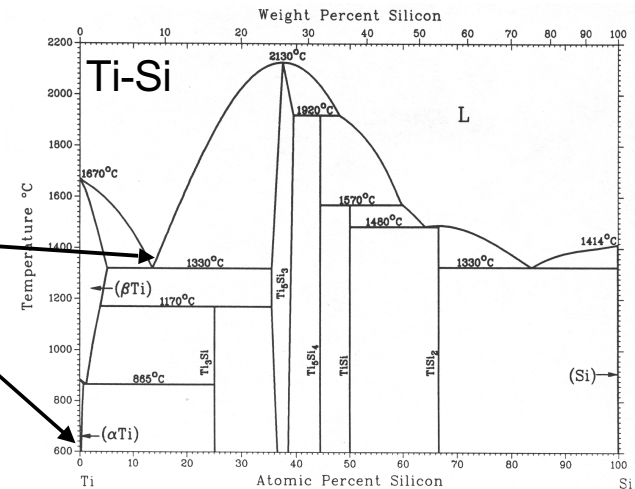
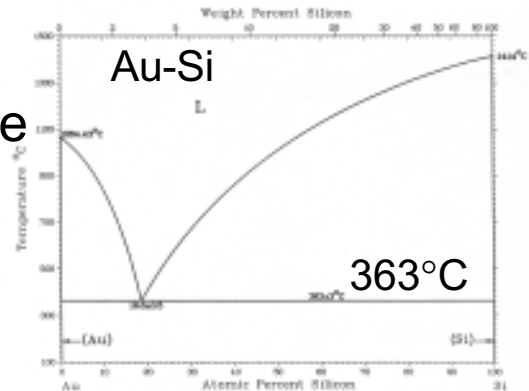
Need barrier layers if used with Si ICs

**Ti:**  $E_t - E_i \sim 0.34 \text{ eV}$

$N_{ss} \sim 10^{12} \text{ cm}^{-3}$

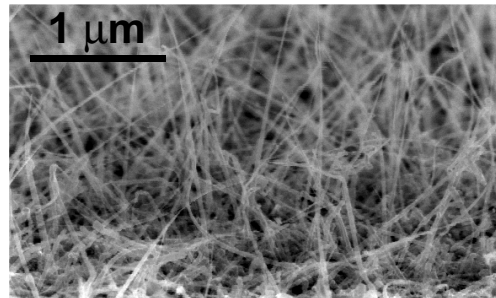
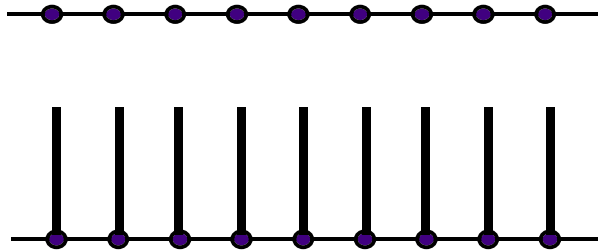
Liquid eutectic:  $1350^\circ\text{C}$

Deposition temperature:  $\sim 600^\circ\text{C}$   
(probably not VLS growth)



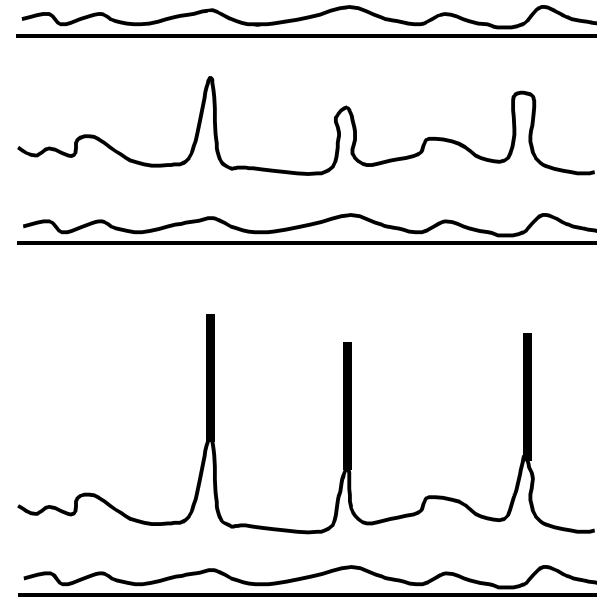
# Catalytic Nuclei: Form

## Isolated Nuclei



Si on evaporated Ti  
Si grown at ~620°C

## Layer

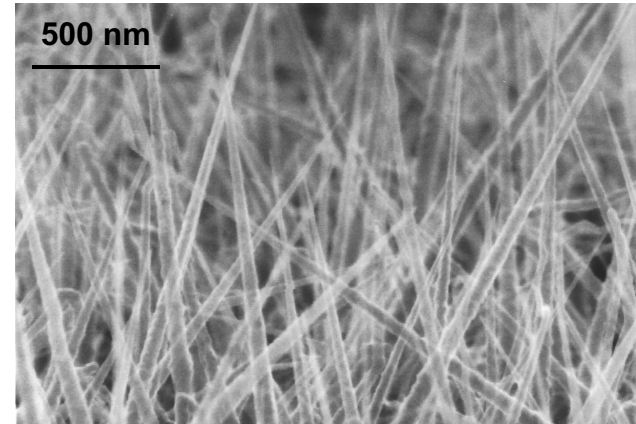
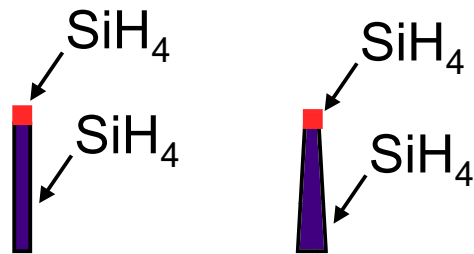


## Si Nanowires on Ti

Wire diameter: 20-40 nm

Tapered at higher temperatures

Uncatalyzed growth on sides of wires



Reduce taper by limiting uncatalyzed deposition rate

Reduce temperature

Less reactive Si source: eg,  $\text{SiH}_2\text{Cl}_2$

Add HCl

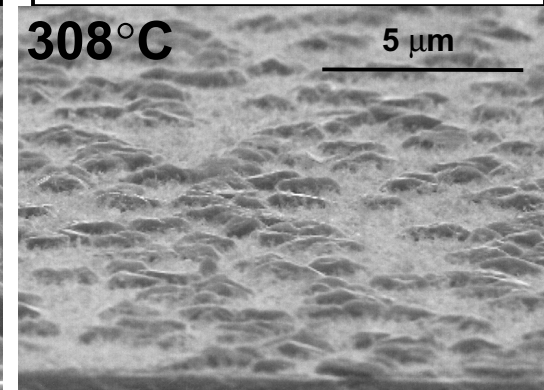
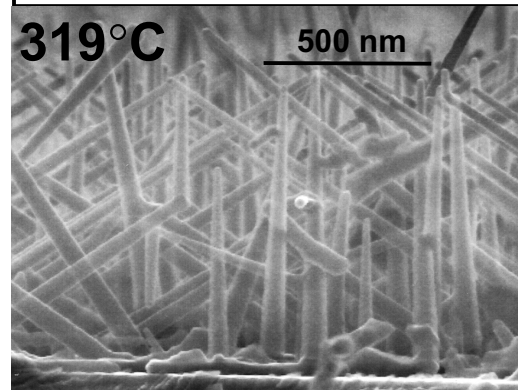
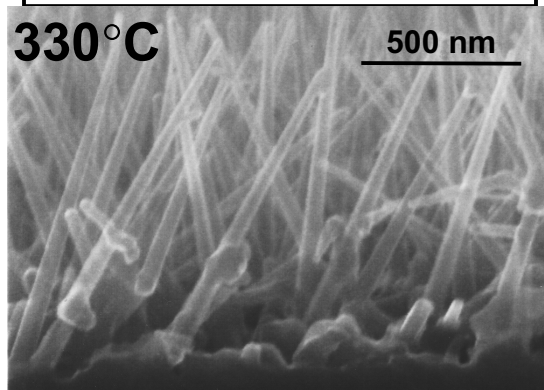
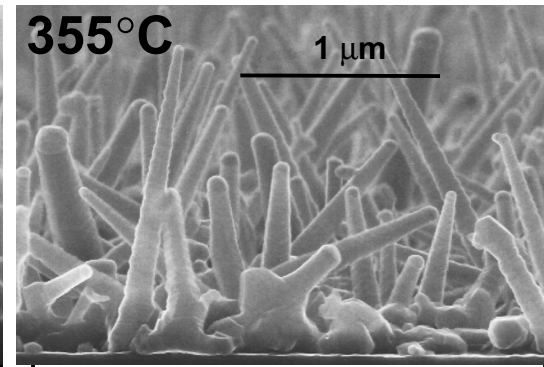
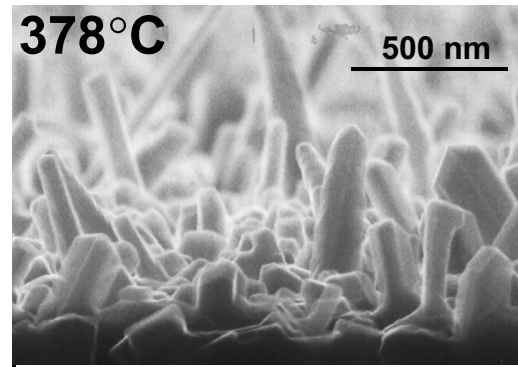
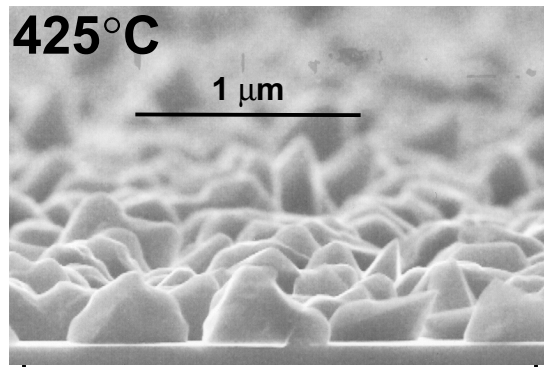
Nanowires formed in 600°C temperature range:

Compatible with partially processed CMOS

# Lower Temperatures for CMOS Compatibility Ge Nanowires on Au Nanoparticles

Temperature range for wire growth:  $\sim 315\text{--}370^\circ\text{C}$

Wire diameter  $\sim 40\text{ nm}$  on  $\sim 20\text{ nm}$  Au nanoparticles



## Stability of Si Nanowires

How stable are nanowires?

Process integration easier if more stable

Instability caused by surface diffusion

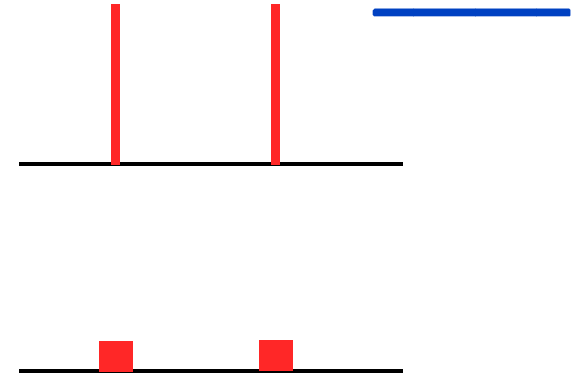
Native oxide expected to stabilize

Consider different ambients

Inert vs. reducing

Intermediate air-exposure

(In-situ vs. ex-situ annealing)



Inert ambient after air exposure:  $N_2$ :

Stable to  $>950^\circ C$

Slightly reducing ambient after air exposure:  $4\%H_2/N_2$

Also stable to  $\sim 950^\circ C$

Strongly reducing ambient after air exposure:  $H_2$

Strongly reducing ambient - no air exposure:  $H_2$

## Stability of Si Nanowires

How stable are nanowires?

Process integration easier if more stable

Instability from surface diffusion

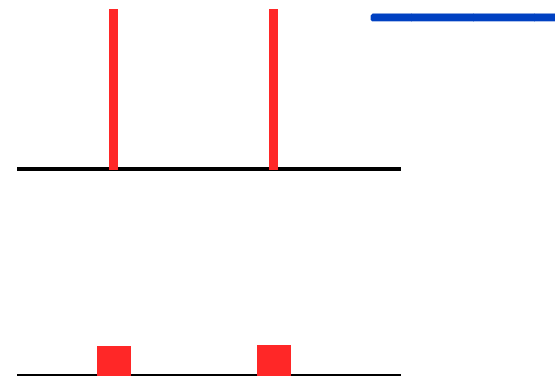
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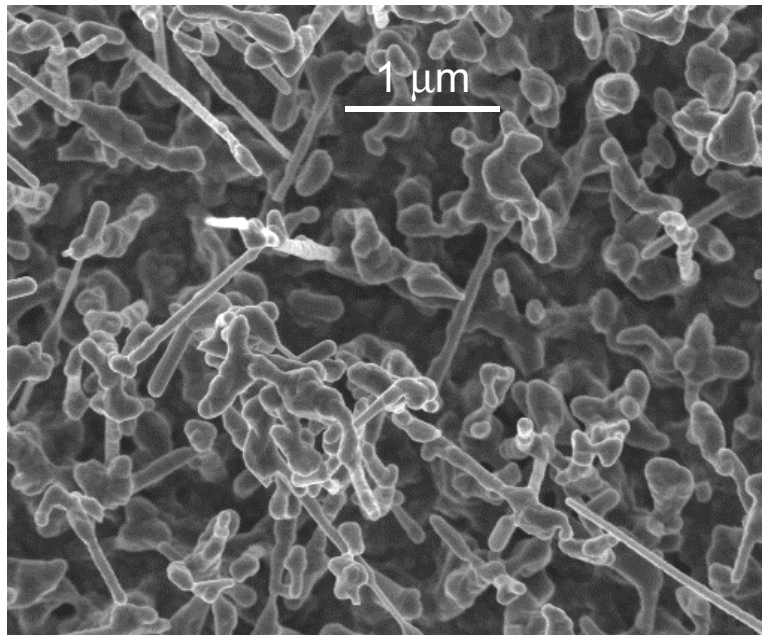
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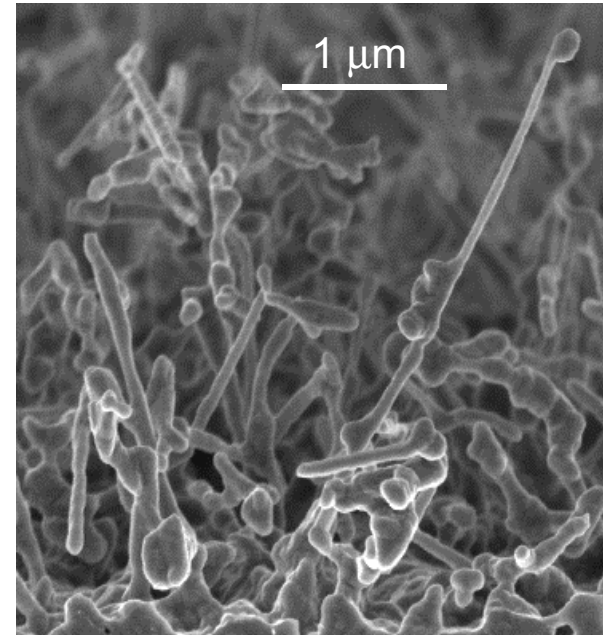
Strongly reducing ambient after air exposure:  $H_2$

Strongly reducing ambient - no air exposure:  $H_2$

**Stability (or lack of): 900°C in H<sub>2</sub>**  
**Si Nanowires on Ti**

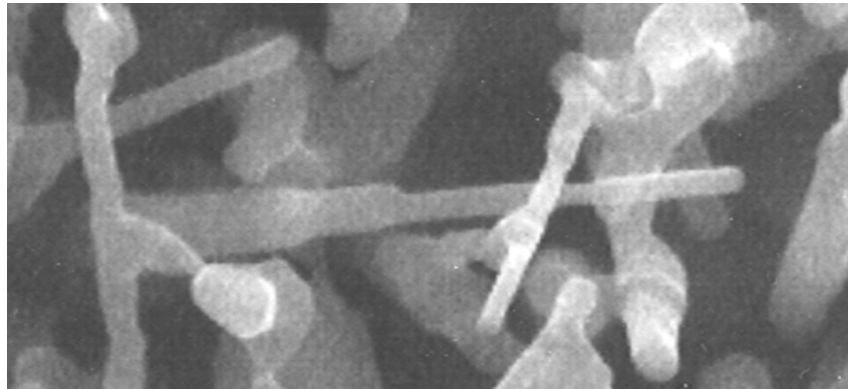


(Plan view)

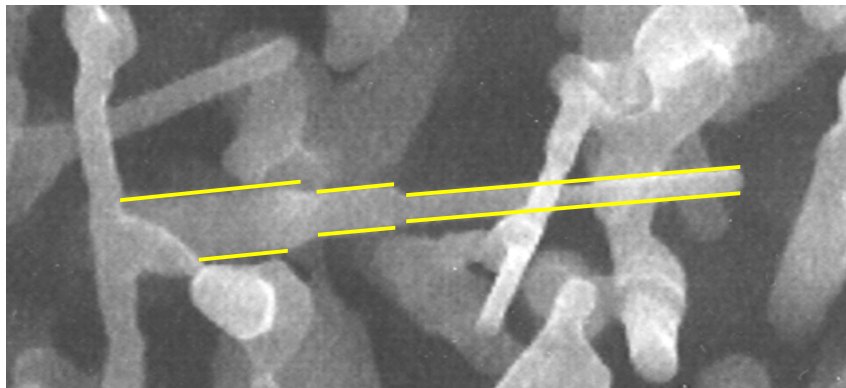


(Cross section)

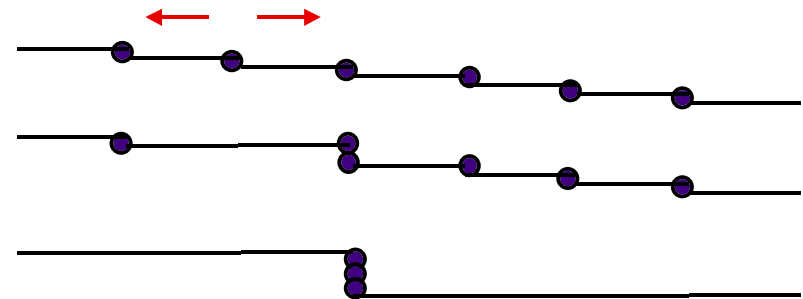
## Step Bunching on Tapered Nanowire



1 μm

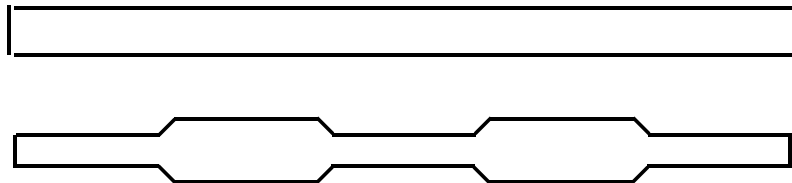
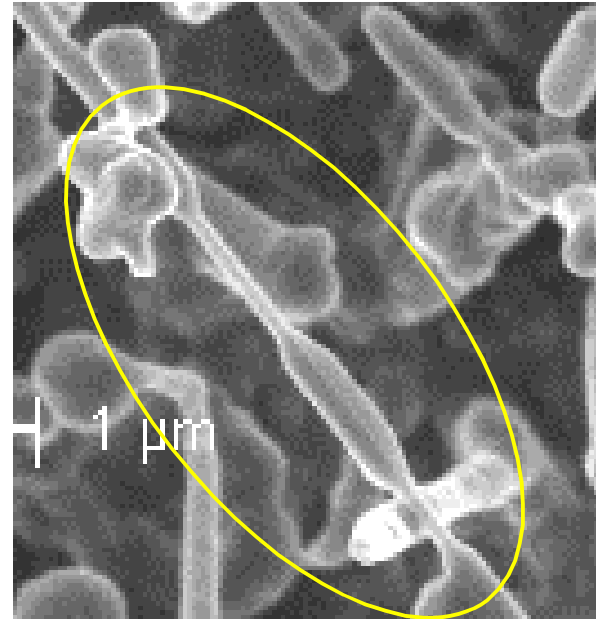
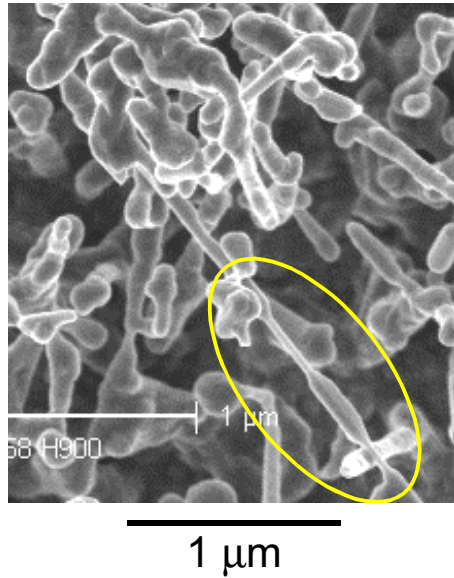


Rapid surface diffusion  
Limited by step  
detachment/attachment





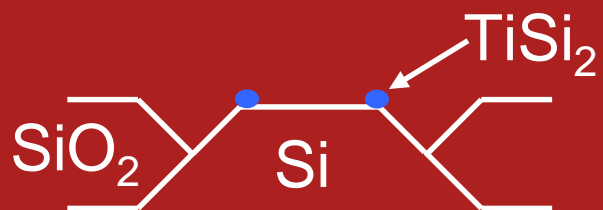
## Instability along Uniform Nanowire



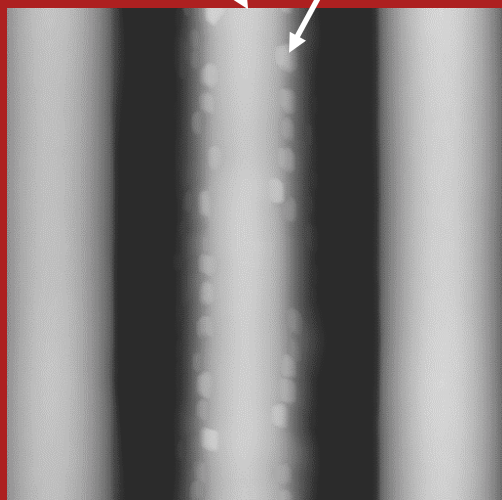
F. A. Nichols and W. W. Mullins, *Trans. Met. Soc. AIME* **233**, 1840 (1965).  
Lord Rayleigh, *Proc. London Math. Soc.* **10**, 4 (1878).

# Forming Nanowires at Ordered Positions

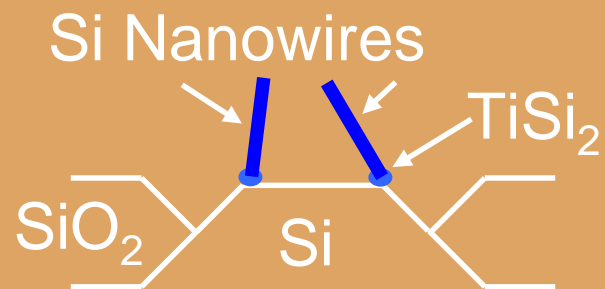
Oxide-Patterned Si Substrate



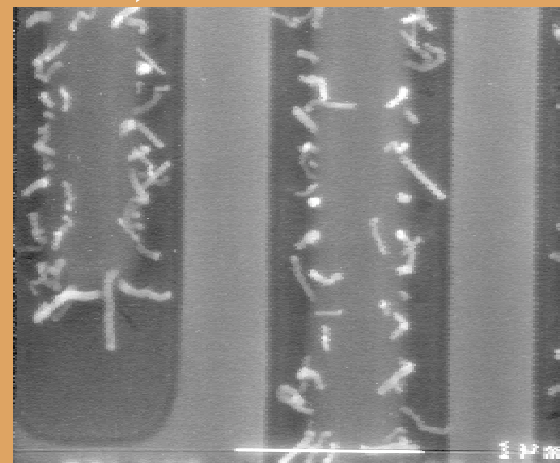
Si TiSi<sub>2</sub> islands



Oxide



Si wires



# Forming Self-Assembled Islands (Quantum Dots)

## Deposit one material on another

Different lattice constants → strain

Large strain → islands

Small islands → quantum or  
Coulomb-blockade effects

## Focus on Ge on Si

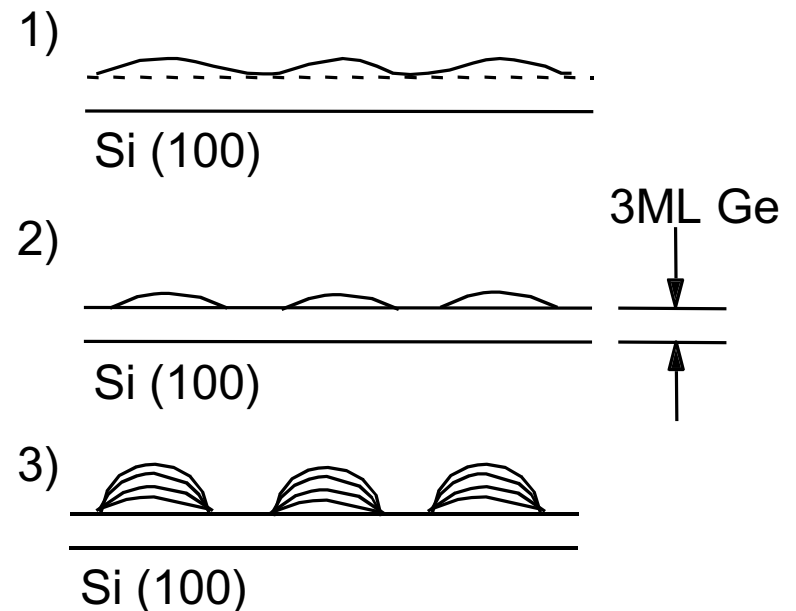
Why Ge on Si?

Compatible with Si IC technology

Deposition by

Chemical Vapor Deposition  
(or Physical Vapor Deposition)

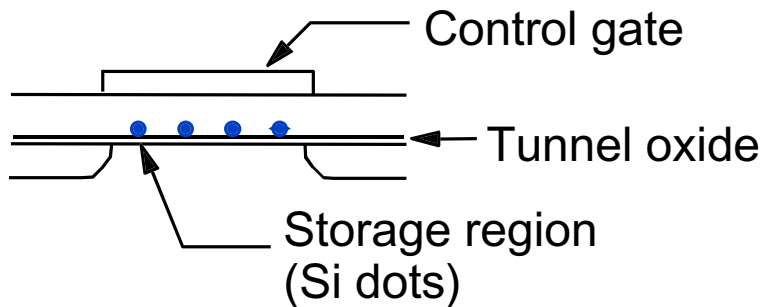
## Energy and Kinetics Influence Island Formation



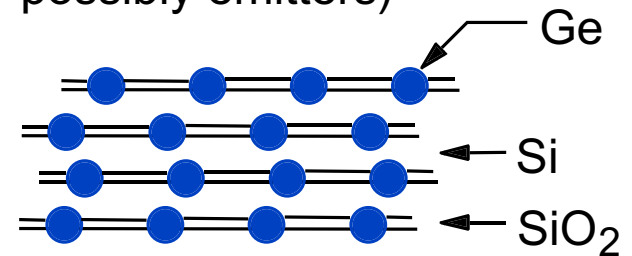
# Possible Device Applications

## Random Arrangement

Nonvolatile memory



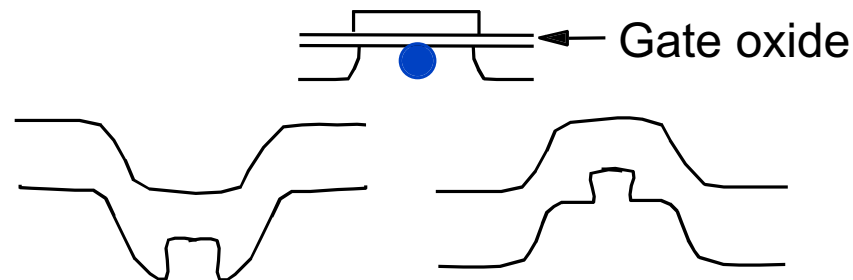
Long-wavelength photodetectors  
(or possibly emitters)



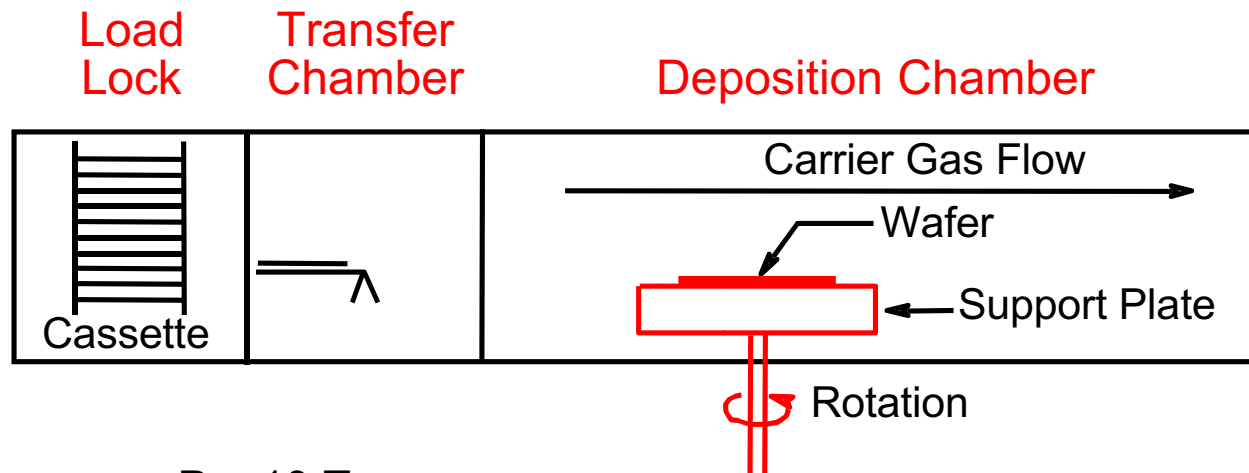
## Aligned

MOS for logic

Possible barrier to short-channel (substrate) effects



# Chemical Vapor Deposition Reactor



$P \sim 10$  Torr

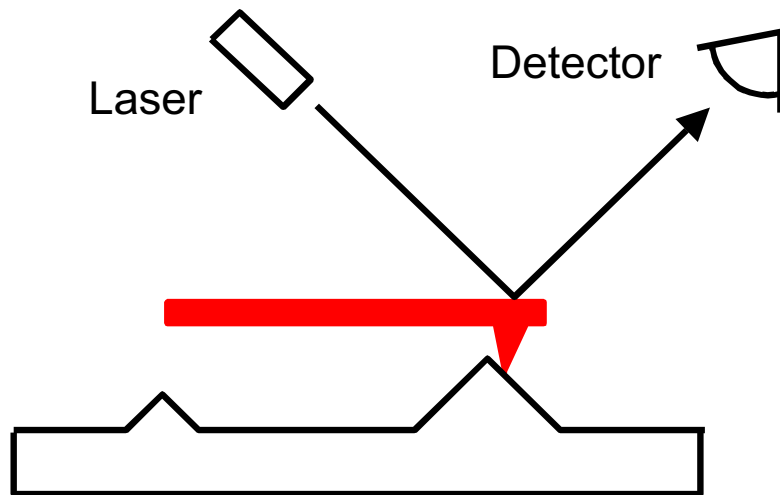
Carrier gas:  $H_2$

Ge source gas:  $GeH_4$

Layers deposited in two different single-wafer CVD reactors  
(and also by PVD)

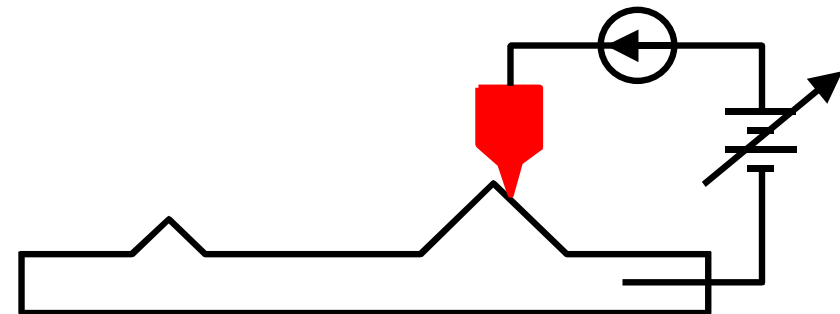
# Scanning-Probe Microscopy

## Atomic-Force Microscope (AFM)



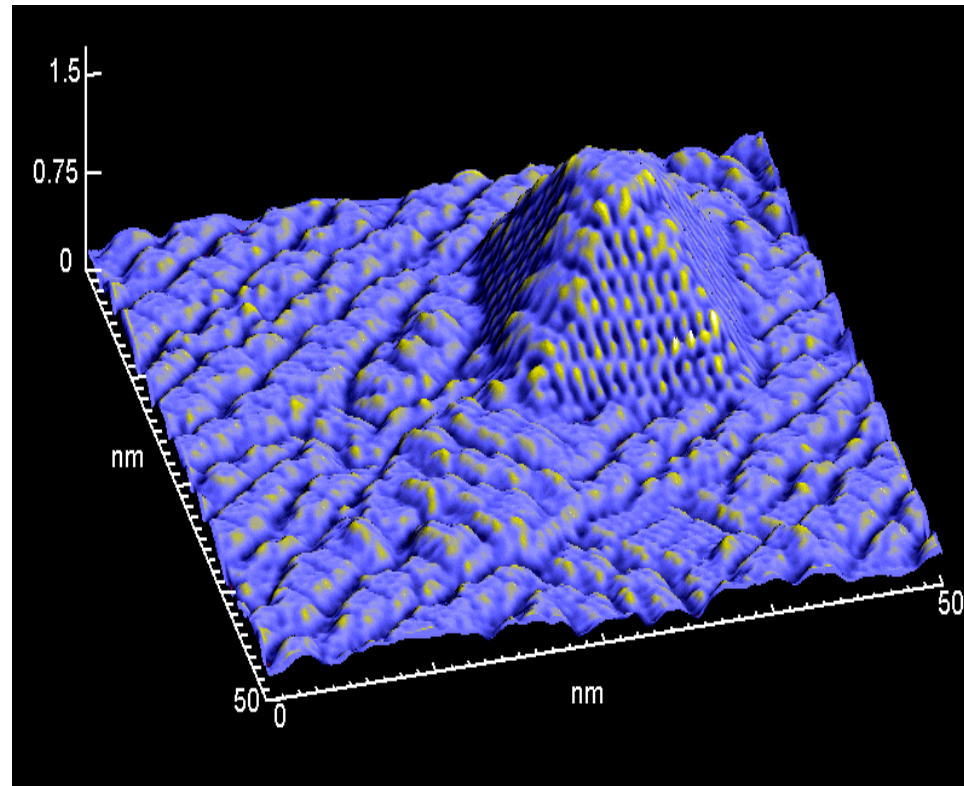
CVD and *ex situ* characterization

## Scanning-Tunneling Microscope (STM)



PVD and *in situ* characterization

## Very Small Ge Pyramid

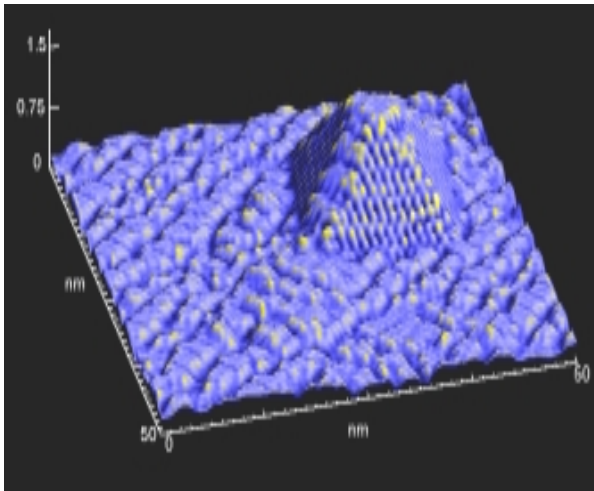


Scanning Tunneling Micrograph by G. Medeiros-Ribeiro, HPL

# Self-Assembled Nanostructures

## Strain from lattice mismatch forms 3D structure

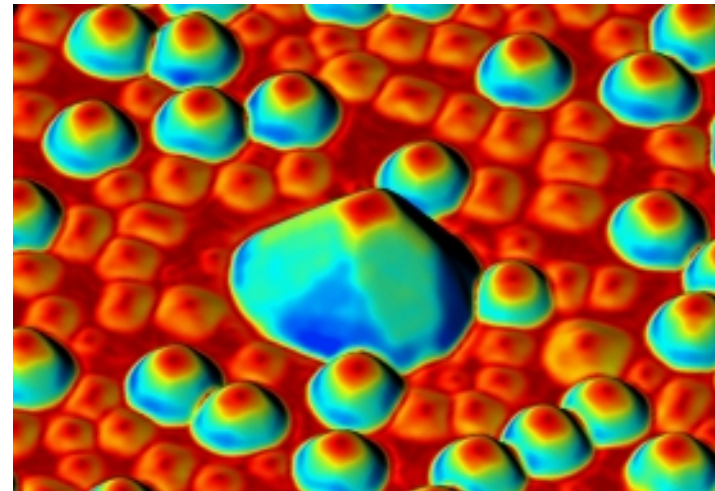
Small Ge “pyramid”  
on Si(001)



Scanning-tunneling  
micrograph

Gio Medeiros-Ribeiro, HPL

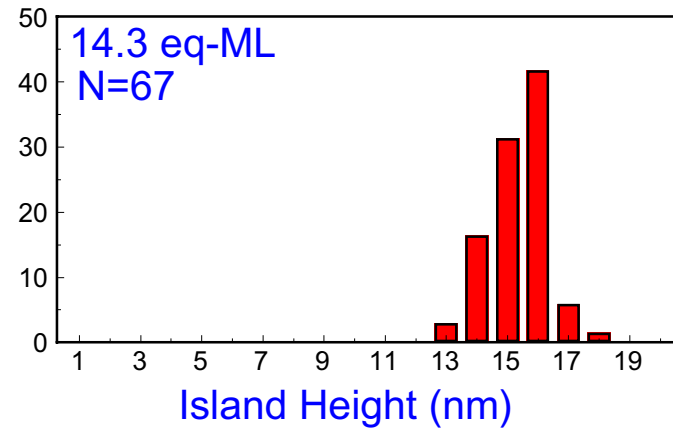
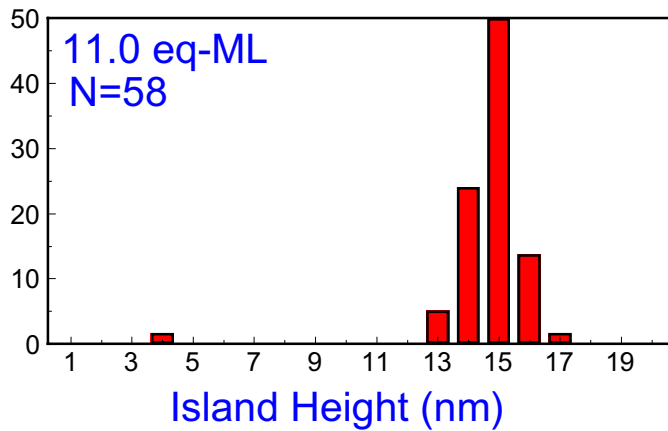
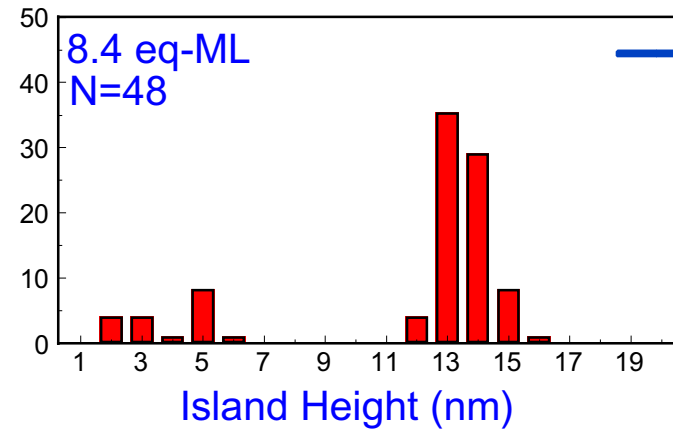
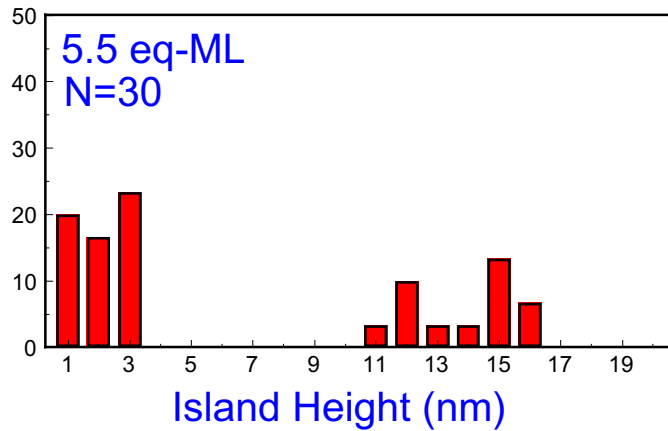
Array of Ge islands:  
Pyramids, domes, superdomes



Atomic-force  
micrograph



# Distribution of Island Heights



Percent of Islands

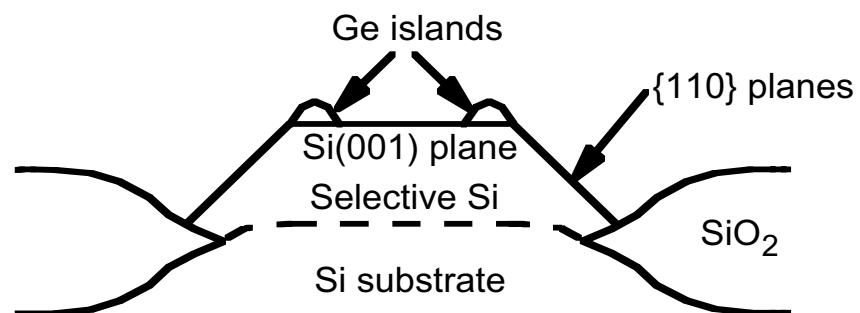
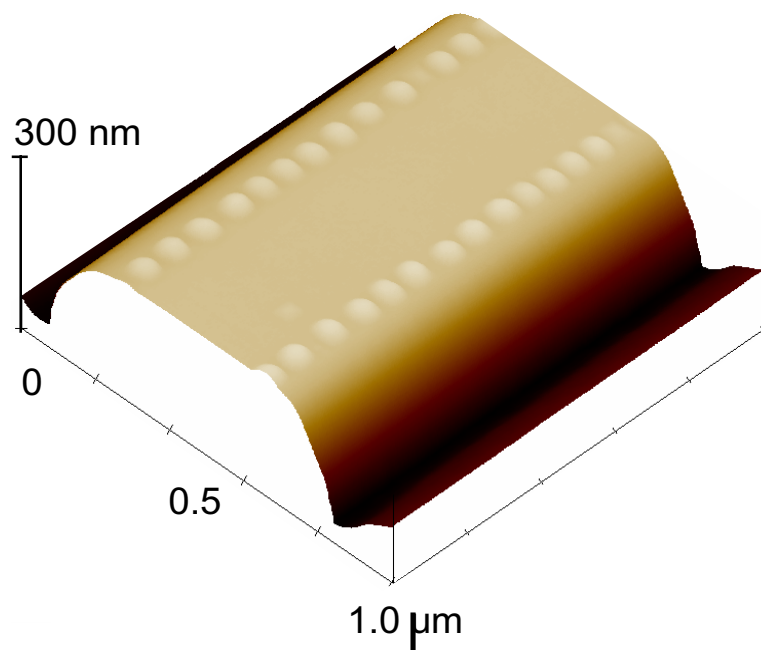
Percent of Islands

Percent of Islands

Percent of Islands



# Positioning Islands: Self-Assembled Ge Islands on Patterned Si substrate

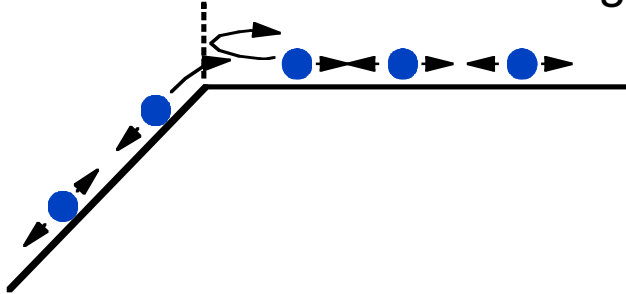


T.I. Kamins and R. Stanley Williams,  
Appl. Phys. Lett. **71**, 1201 (1997)

# What Causes Alignment?

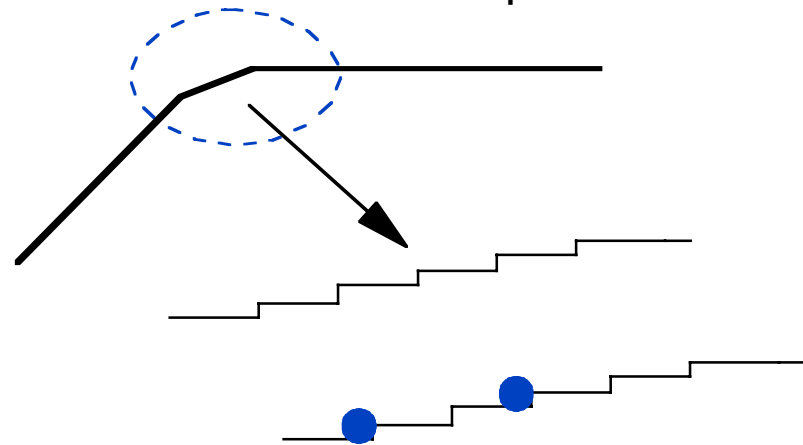
## Surface Diffusion?

Anisotropic diffusion causes  
Ge accumulation near edge



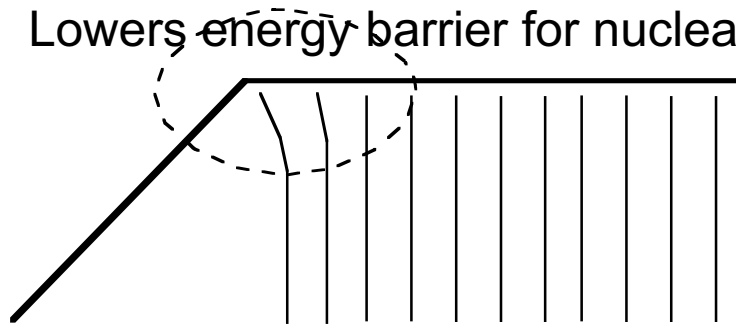
## Steps near Edge?

Small facet at corner provides steps  
Ge nucleates on steps



## Strain?

Ge stretches Si lattice near edges  
Relieves stress  
Lowers energy barrier for nucleation



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# Anisotropic Stress

## Ge on Si:

Lattice mismatch same in x and y directions

⇒ equi-axed islands

Different lattice mismatch in different directions

⇒ anisotropic islands (ie, “wires”)

## Anisotropic lattice mismatch:

ErSi<sub>2</sub> [0001] || Si<110>: +6.5%

ErSi<sub>2</sub> [11 $\bar{2}$ 0] || Si<110>: -1.3%

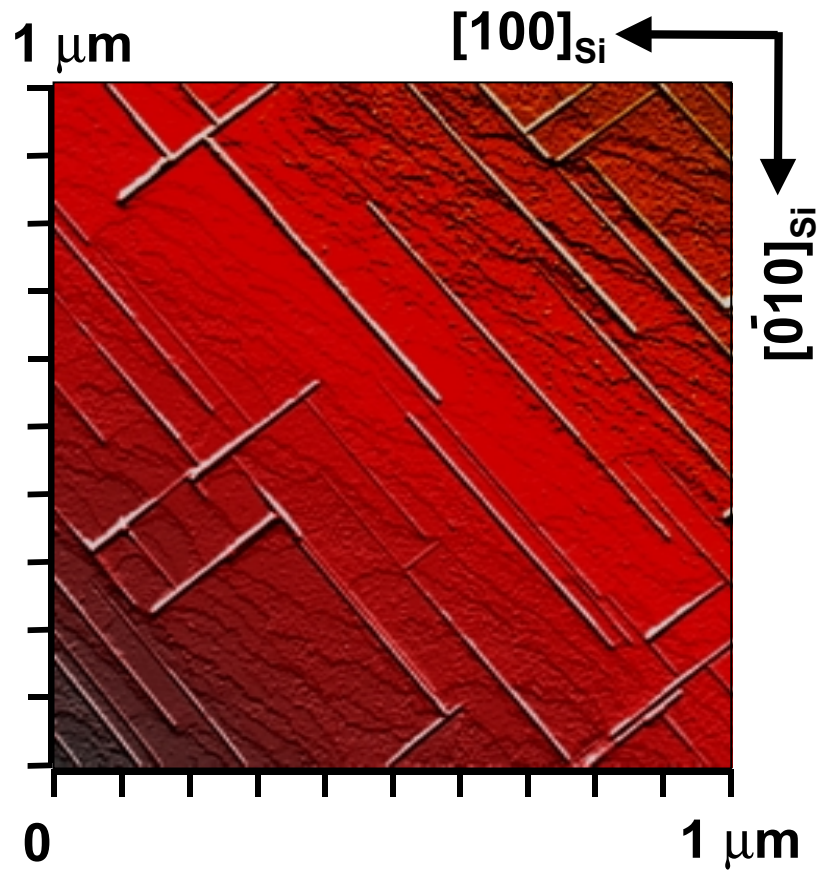
Constraint on growth in one direction

Elongated (wire) growth in perpendicular direction

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Y. Chen, D. A. A. Ohlberg, G. Medeiros-Ribero,  
Y. A. Chang, and R. Stanley Williams,  
Applied Physics Letters **76**, 4004 (26 June 2000)

# ErSi<sub>2</sub> on Si

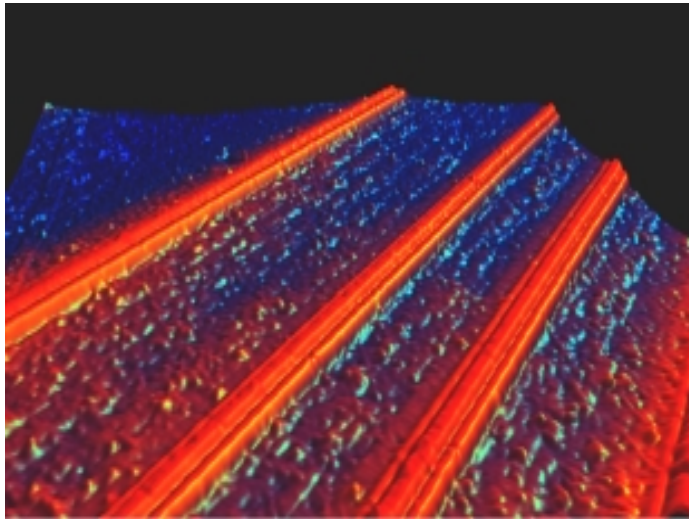


Yong Chen and Doug Ohlberg, HPL

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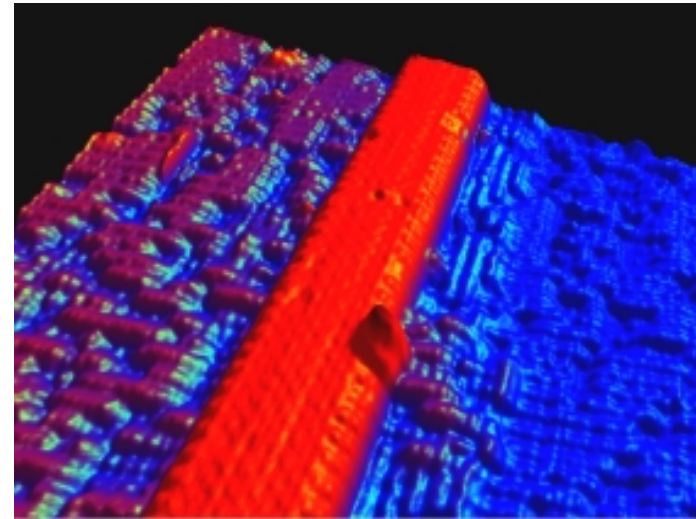
## Self-Assembled Nanostructures

**Anisotropic lattice strain  
forms 1D structure**



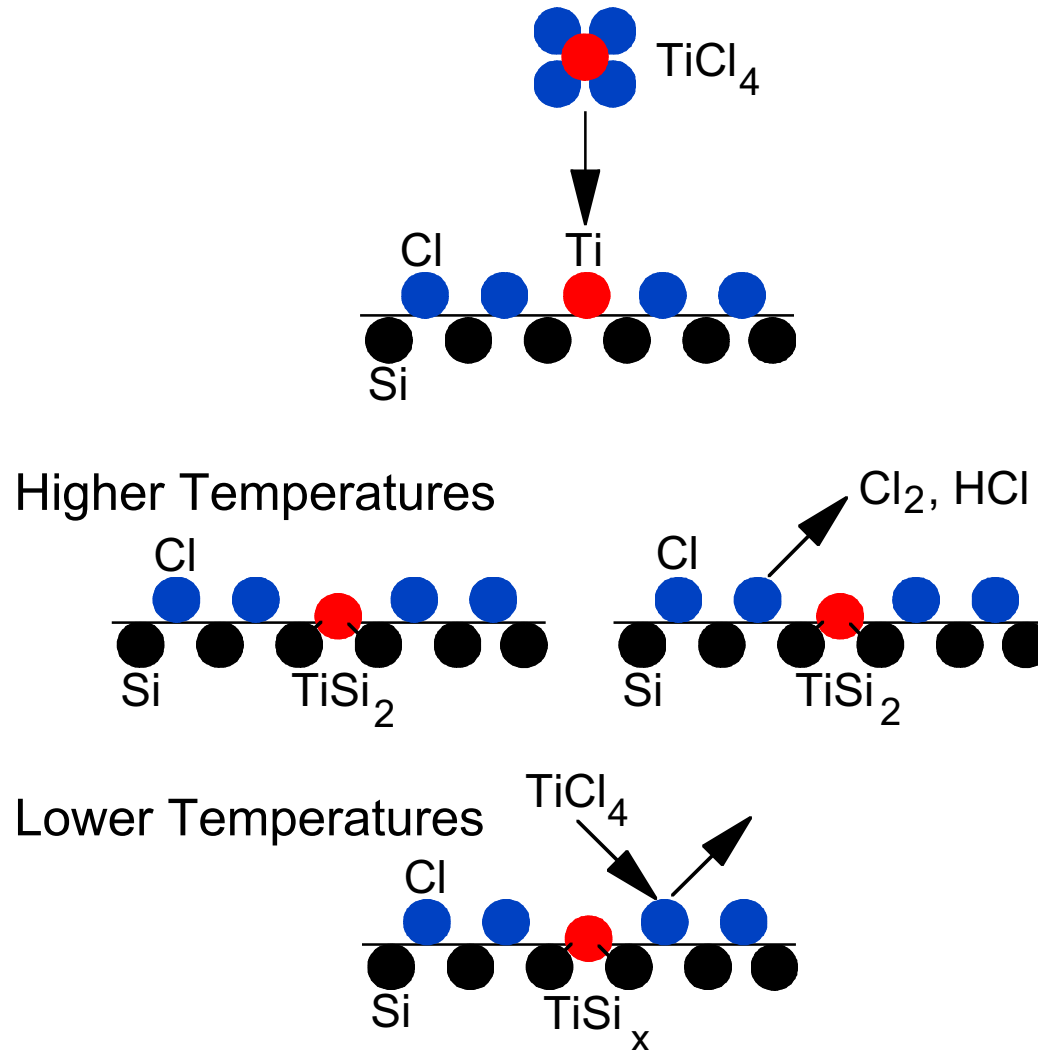
Scanning tunneling  
micrographs

**ErSi<sub>2</sub> “wires” on Si(001)**

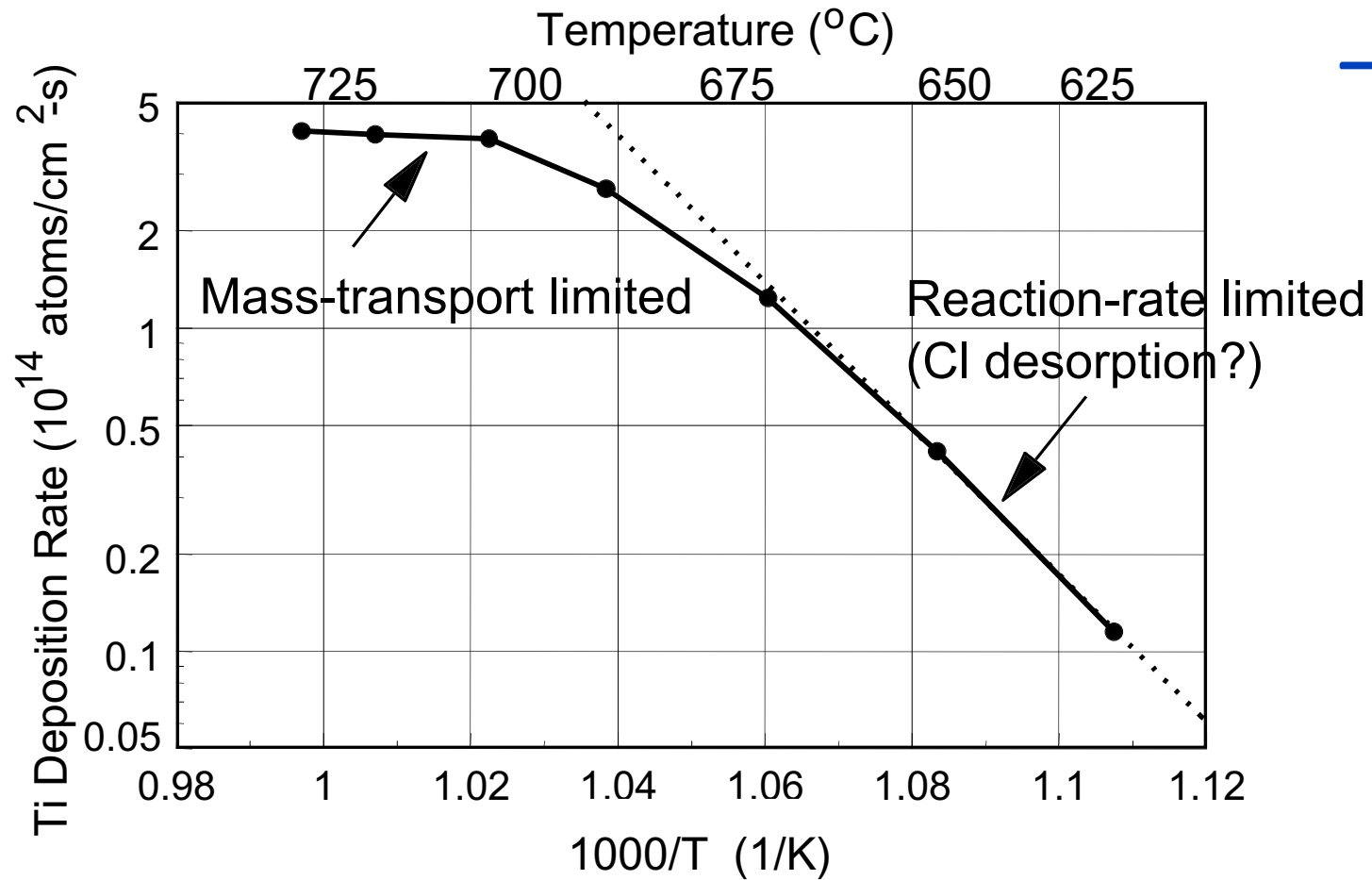


Yong Chen and Doug Ohlberg, HPL

# Deposition of Ti from $\text{TiCl}_4$

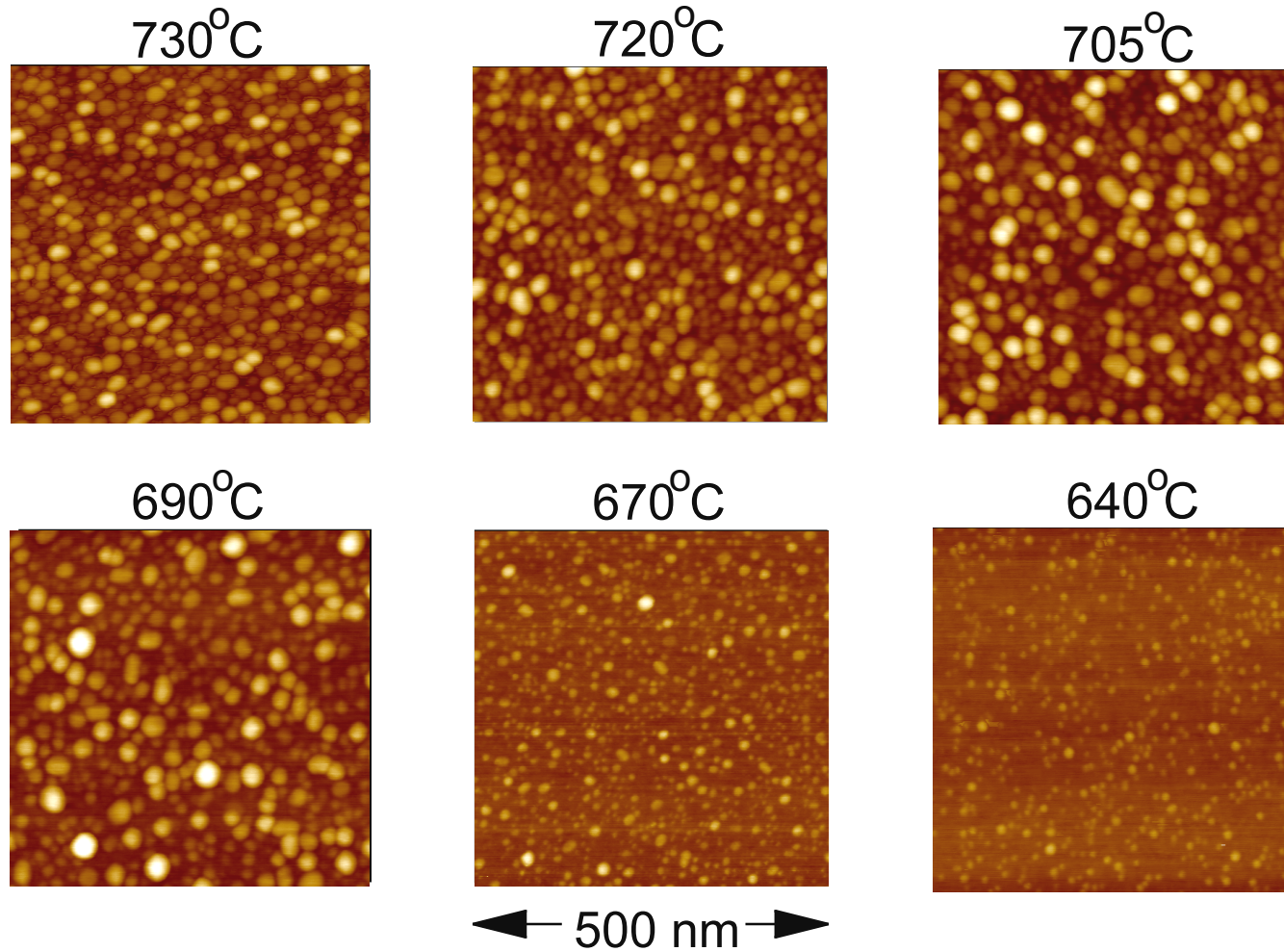


# Deposition Rate of Ti from $\text{TiCl}_4$



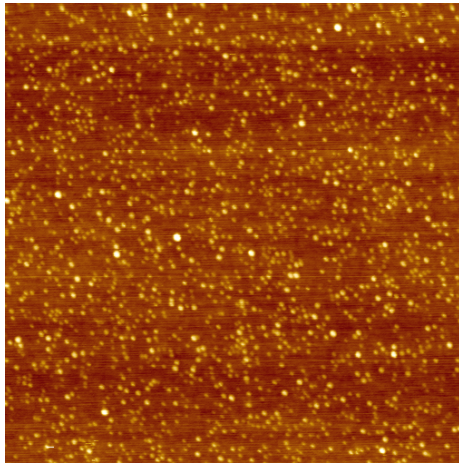


# Deposition of Ti from $\text{TiCl}_4$

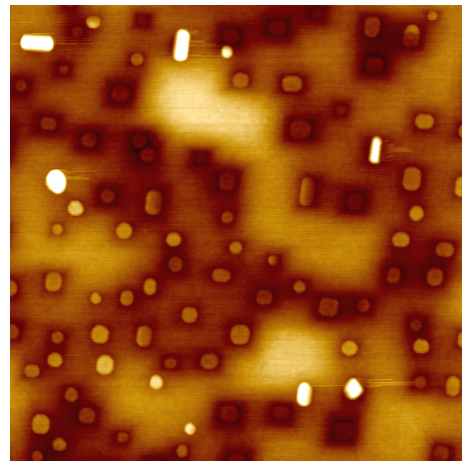


# Annealing CVD Ti Islands

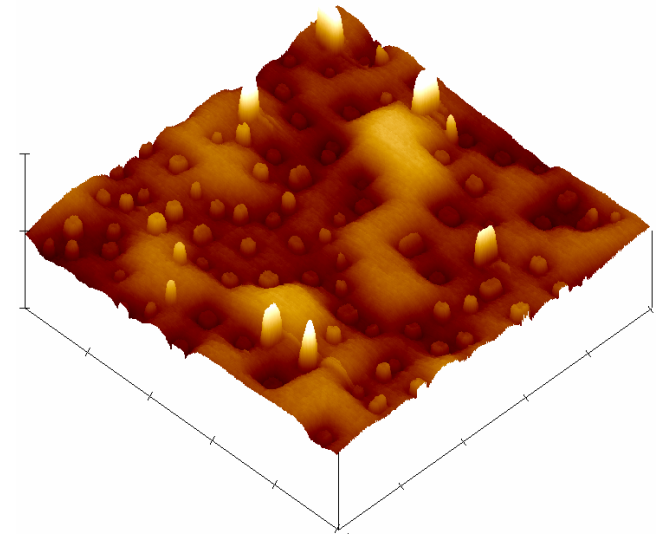
After Deposition at 640°C



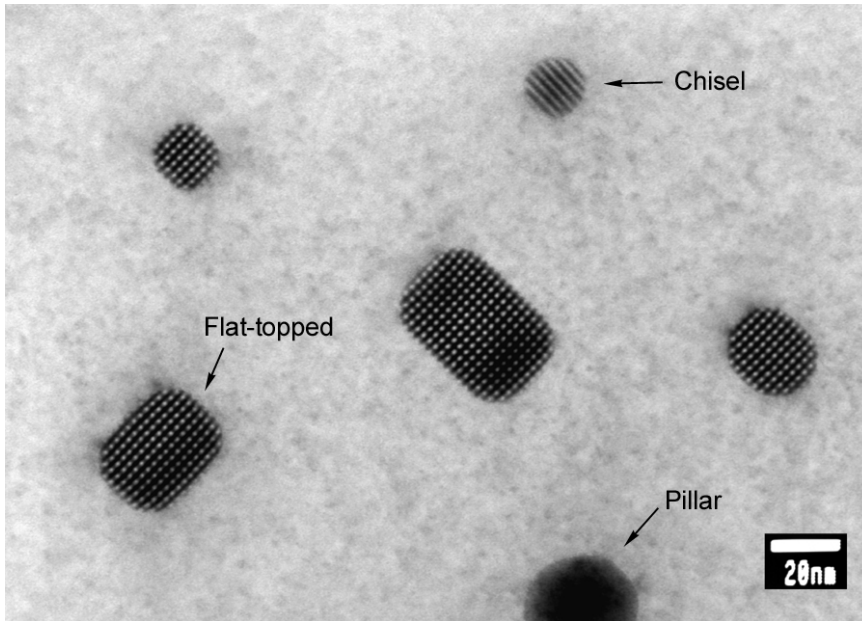
Annealed at 920°C



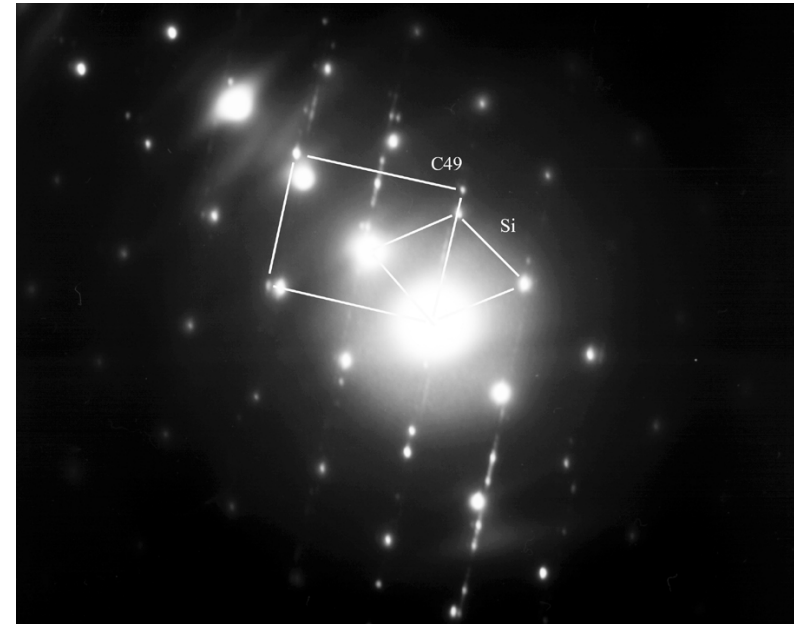
1.0 μm



# Transmission Electron Microscopy of Annealed $\text{TiSi}_2$ Islands



Plan View



Cross Section

Transmission electron microscopy by  
David Basile and Margaret Wong of  
Agilent Laboratories

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## Nanowire: Integrated Device and Interconnection

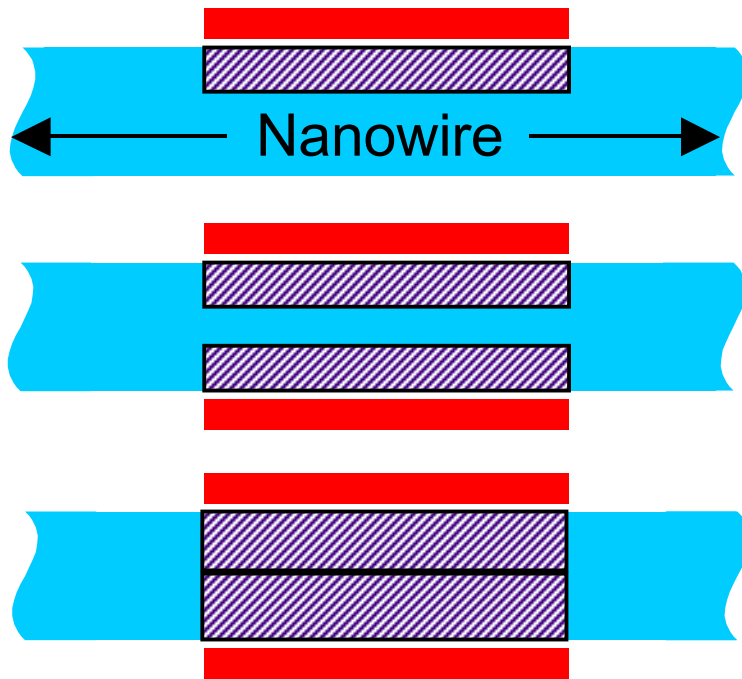
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### **Trade-off: Series resistance vs. Transistor Characteristics**

Two cases: Uniform doping  
Selective doping

## Nanowire: Uniform Doping



Normally ON transistor

$$D < 2 x_{dmax}$$

Doping low enough so can deplete  
entire wire diameter

Limits conductance of interconnect

Voltage drop along wire

Time to charge next gate

Sensitive to size and doping

# Selective Doping



Interconnection

Device

Interconnection

Bulk (e.g., implant)

Surface induced

Heavy doping  
(~sol.sol.)

Light doping  
(~ intrinsic or  
opposite type)

Normally OFF transistor

$$D \not\leq 2 x_{dmax}$$



Induce channel

Intrinsic: Not sensitive to dopant fluctuations

Sensitive to wire diameter

# Addressing Moore's Second Law

## Crossbar Array

### **Dense**

Device at intersection of two wires

### **Structurally simple**

Need well-defined threshold to  
avoid switching when "half selected"

### **Repetitive**

Allows reconfiguration

Defect tolerance

### **Wires (perhaps)**

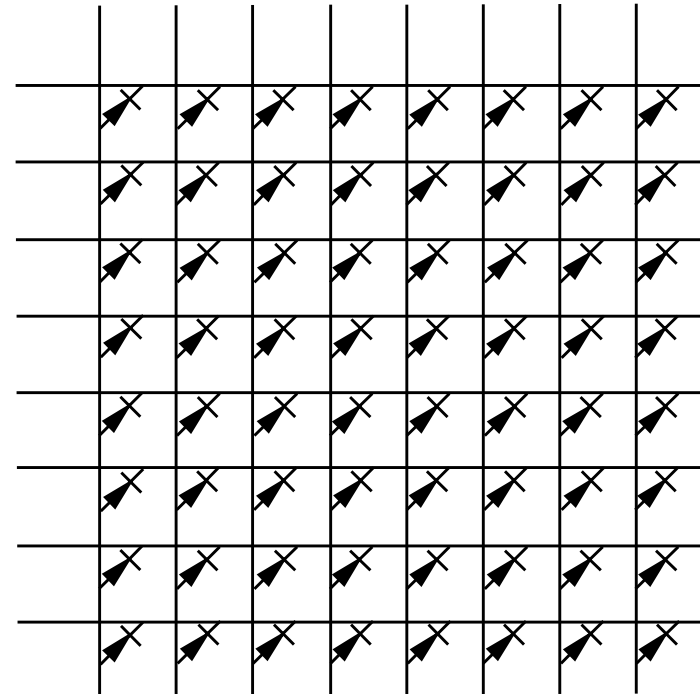
Si nanowires or C nanotubes

### **Gain**

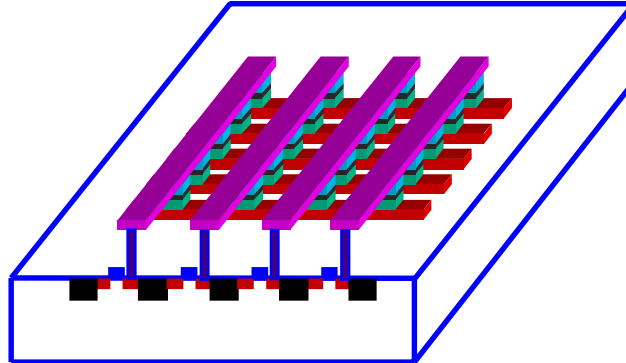
In devices

In "wires"

In underlying CMOS



## Cross-Bar Memory Array above Logic



### **Bit at crossing of wires**

Nonvolatile (unlike DRAM)

### **Can be built above CMOS**

Physically place elements closer together

Minimize delay between logic and storage

### **Multiple layers possible** (unlike Flash memory)

“3D IC”

Increase density

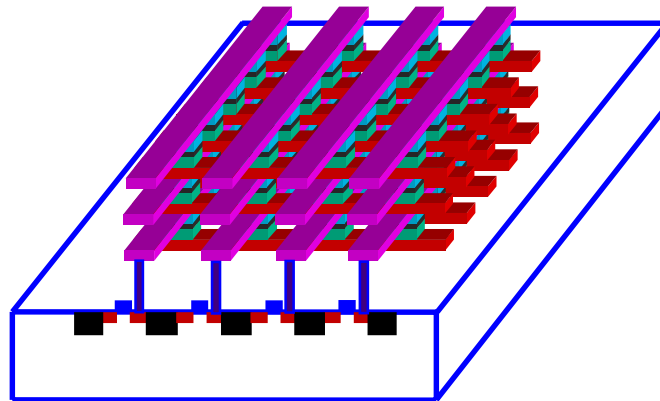
Effective use of expensive CMOS area



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## Three-Dimensional Electronics

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Increase density

Physically place elements close together

Shorter wires

Wires and vias must not limit area  
available for devices

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## Defect Tolerance

**Self-assembled, self-ordered system will not be perfect**

Several percent defects

**How to live with less-than-perfect parts in a system?**

Structurally simple architecture (eg, crossbar array)

Self-assembled parallel straight wires

Map defects

Configure around defects

(Can also be applied to conventional fabrication to reduce costs)

## Teramac (HP Labs Project)

Demonstration of configurable computer made with “known bad” parts  
(location of defects initially unknown)

Implemented with partially defective FPGAs

Mainly wires, crossbar switches, look-up tables

**Normal computer:** Design (configure), build, test

**Teramac:** Build, test (to locate defects), configure around defects



W.B. Culbertson, R. Amerson, R.J. Carter, P. Kuekes, and G. Snider,  
Proc. 1997 IEEE Symp. On FPGAs for Custom Computing Machines  
J.R. Heath, P.J. Kuekes, G.S. Snider, and R. Stanley Williams, Science,  
vol. 280, pp. 1716-1720 (12 June 1998)



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# Summary

## Limits of scaling

### Alternative devices

Single-electron transistor  
Quantum cellular automata  
Molecular electronics  
Quantum computing

## Self-assembled nanostructures

Forming small structures  
Putting them where we want them  
Metal-catalyzed wire growth  
Ti-catalyzed Si nanowire growth  
Stability of wires  
Strain from lattice mismatch  
Zero-dimensional islands: Ge, Ti  
One-dimensional wires: ErSi<sub>2</sub>  
Patterned substrate to position features  
Speculation about nanowire transistor

## Defect-tolerant architecture

